

WaveMaster 8 Zi-B Oscilloscopes 4 GHz-30 GHz



Key Features

- Up to 30 GHz bandwidth and 80 GS/s sample rate
- Most advanced oscilloscope user interface makes configuring complex measurements easy
- The industry's only true hardware
 14.1 Gb/s serial pattern trigger
- Add the Teledyne LeCroy HDA125
 High-speed Digital Analyzer to
 create the most powerful, flexible
 mixed-signal test solution available
- Low Jitter Measurement Floor and exceptional timebase stability
- Comprehensive set of serial data analysis, debug, validation and compliance tools
- Integrated 50 Ω and 1 M Ω inputs for true connection and probing flexibility
- Integrated standard and custom measurements and math functions for unrivaled analysis capability
- Multi-lane serial data eye, jitter and crosstalk analysis

The WaveMaster 8 Zi-B combines the performance, signal fidelity and feature set needed for today's high-speed measurements with the ease-of-use of a standard benchtop oscilloscope. Featuring the highest-speed serial data triggers, the only complete multi-lane serial data analysis and eye diagram solution, and the most comprehensive set of compliance packages, the WaveMaster 8 Zi-B simplifies the most complex testing.

Exceptional Performance

With up to 30 GHz bandwidth, 80 GS/s sample rate, low noise, an extremely stable time base and a 14.1 Gb/s serial trigger the WaveMaster 8 Zi-B has the hardware performance to capture today's high-speed signals.

Most Advanced User Interface

Teledyne LeCroy's MAUI user interface puts the deepest measurement toolset of any oscilloscope at your fingertips. Coupled with the WaveMaster 8Zi-B's 15.3" high-resolution touchscreen, MAUI makes advanced analysis easy to set up and use. A flat menu structure puts the most common tools in the easiest reach. Sophisticated multi-grid displays are simple to configure. Vertical, horizontal and acquisition setting changes are made without obscuring waveform display.

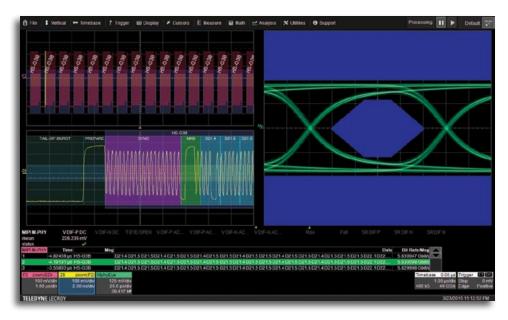
Advanced Waveform Processing

A powerful PC with a 3.1 GHz quad core processor and up to 32 GB of RAM enables fast waveform processing for the most advanced analysis. User-defined mathematical functions and measurements are available natively, or through seamless integration with external environments like MATLAB.

Complete Characterization, Compliance Testing and Debug

The WaveMaster 8 Zi-B provides the most powerful analysis tools. SDAIII-CompleteLinQ simultaneously displays eye diagrams and breaks down jitter on four signals. EyeDrII and VirtualProbe options analyze lane interactions using S-parameter files. Crosstalk tools analyze amplitude noise. QualiPHY software simplifies and automates compliance testing and reporting for a wide range of serial data standards.

MAUI - THE MOST ADVANCED USER INTERFACE



WaveMaster 8Zi-B's advanced MAUI user interface combines multiple analysis types into a single, correlated display:

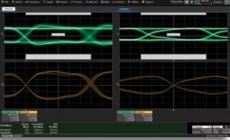
- Analog signals
- Protocol decodes
- Eye diagrams
- Jitter and noise breakdown
- Measurement parameters
- Frequency-domain traces



Decode From Bit-level to Protocol Layer

Decoders are available for over 20 low-speed and high-speed serial data buses. These fully-integrated analysis tools annotate the acquired analog waveform with the corresponding decoded data, as well as providing a comprehensive, exportable decode table.

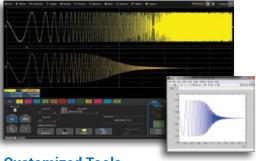
For many standards, ProtoSync allows a view from even higher up the protocol stack, linking the physical-layer waveforms to full transaction- and protocol-layer analysis.



Comprehensive Physical Layer Analysis

The WaveMaster 8Zi-B has the largest toolkit for characterizing signal integrity and debugging physical layer problems:

- SDAIII CompleteLinQ the most complete NRZ signal analysis package available for any oscilloscope
- DDR Debug: the only toolkit specifically for validating and troubleshooting DRAM designs
- Decode and physical-layer test packages for MIPI M-PHY and D-PHY
- PAM4 analysis for leading-edge multilevel signal analysis



Customized Tools

With the MAUI user interface, thirdparty programs can be completely integrated into the oscilloscope's processing stream. Create customized math functions and parameters using C/C++, MATLAB, Excel, JScript or Visual Basic without ever leaving the oscilloscope application - and view the results directly on the oscilloscope, in real-time.

SDA8ZI-B SERIAL DATA ANALYZER











WaveMaster 8 Zi-B

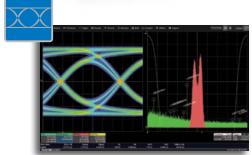
SDAIII Eye and Jitter Analysis

Extended Acquisition Memory

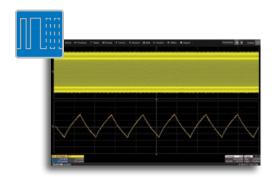
High-speed Serial Triggering



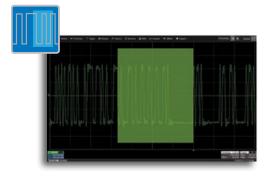
With its combination of high bandwidth, excellent signal fidelity, and the most complete toolset in its class, the WaveMaster 8 Zi-B is the ideal platform for high-speed serial data analysis. The SDA 8 Zi-B models have been specifically configured to handle today's most challenging serial data applications:



The SDA 8 Zi-B comes standard with the SDAIII core toolset, providing tightly-integrated and comprehensive eye diagram and jitter analysis for NRZ signals. SDAIII easily emulates complex clock recovery and PLL behavior, and quickly renders eye diagrams using all acquired unit intervals. Jitter analysis includes Rj - Dj separation, Tj extrapolation, measurements of DDJ, ISI, and Pj, and visualization using histograms, tracks, and jitter spectra.



With 64 Mpts on all four input channels, the SDA 8Zi-B doubles the WaveMaster's standard acquisition memory. Serial data analysis puts a particular set of demands on an oscilloscope's timebase capabilities. Decoding up to protocol level typically requires the acquisition of long waveforms. Likewise, slowly-varying physical-layer characteristics such as Spread-Spectrum Clocking (SSC) must be analyzed over periods of milliseconds.



The SDA 8Zi-B comes standard with a true hardware high-speed serial pattern trigger, to ensure capture of even the rarest pattern at up to 6.5 Gb/s. The trigger also natively triggers on 8b/10b and 64b/66b words, with corresponding decoders included in the SDA configuration. And if 6.5 Gb/s is not enough, the high-speed serial trigger can be upgraded to an industry-leading 14.1 Gb/s.

THE MOST CAPABLE HARDWARE PLATFORM

The WaveMaster 8 Zi-B is built on an exceptionally accurate acquisition system, with pristine signal fidelity and high timebase stability. Coupled with the most flexible set of inputs and the highest-performance serial trigger, it represents the most versatile platform in its class.

- Pristine high-bandwidth performance:
 - Up to 30 GHz bandwidth, 80 GS/s sample rate,
 512 Mpts of analysis memory on 2 channels
 - Up to 20 GHz bandwidth, 40 GS/s sample rate,
 256 Mpts of analysis memory on 4 channels
 - Exceptionally accurate and stable timebase -100fs (rms) timebase jitter
- Bandwidth upgrade capability from 4 GHz to 30 GHz to maximize investment leverage
- Hardware serial triggering up to 14.1 Gb/s
 - The highest speed true-hardware serial trigger provides capability for 80-bit NRZ serial pattern triggering, 8b/10b and 64b/66b symbol triggering.
 - Teledyne LeCroy's true hardware trigger means even infrequently-occurring patterns can be reliably triggered on and captured. Competing software "serial triggers" risk missing rare events.
 - A 6.5 Gb/s serial trigger is included standard with SDA 8 Zi-B models, upgradeable to 14.1 Gb/s.
 Either serial trigger may be added to WaveMaster 8 Zi-B and DDA 8 Zi-B models.
- The only high-bandwidth oscilloscope to support both 50 Ω and 1 M Ω inputs on the same instrument without the use of cumbersome external adapters.
- Add HDA125 High-speed Digital Analyzer via the integrated LBUS connector to give 18 digital channels at 12.5 GS/s each - for the most advanced mixed-signal test system available.



SUPERIOR ANALYSIS AND INSIGHT



The WaveMaster 8 Zi-B's MAUI advanced user interface combines the deepest toolset with simple operation, making it easy to configure sophisticated measurements. The operating software is seamlessly integrated with the hardware platform, providing the best responsiveness and ease of use in its class.

- The most complete set of measurement and analysis tools in the industry leverage powerful processing capability to provide deeper insight in less time.
- Intel® Core™ i7-4770S Quad-core, 3.1 GHz (per core, up to 3.9 GHz in Turbo mode) CPU with 8 GB of RAM (upgradeable to 32 GB)
- High resolution 15.3" WXGA widescreen color touch screen display.
- X-Stream II streaming architecture 10-100 times faster analysis and better responsiveness than other oscilloscopes
- QualiPHY serial data compliance packages speed up testing times and reduce complexity with fully automated compliance packages for PCI Express®, DDR memory, USB 3.0, and many other standards.
- Crosstalk and Vertical Noise Analysis
- SDAIII "LinQ" options provide four simultaneous eye diagrams and jitter calculations for multi-lane serial data link analysis, or for single-lane, multiple location analysis
- Eye Doctor™ II and Virtual Probe Signal Integrity
 Toolsets provide real-time de-embedding,
 emulation, and equalization on serial data
 channels and complex networks
- 325 MB/s data transfer rate from oscilloscope to PC with Teledyne LeCroy Serial Interface Bus (LSIB) option

THE MOST FLEXIBLE MIXED-SIGNAL SOLUTION

Key Features

- 12.5 GS/s sampling rate for 80ps timing accuracy
- 3 GHz leadset for capturing digital signals up to 6 Gb/s
- Add high-speed mixed-signal capability to your Teledyne LeCroy high-bandwidth oscilloscope
 - LBUS connection for precise timing synchronization
 - USB 3.1 for fast data transfer
- Unique QuickLink probing system
 - Differential solder-in tips with
 9-inch lead simplify access to
 difficult test points
 - Ultra low loading for superior performance
 - 6 GHz bandwidth tips are compatible with both HDA digital leadset and Teledyne LeCroy WaveLink differential analog probes for unmatched acquisition flexibility



The HDA125 transforms your Teledyne LeCroy oscilloscope into the highest-performance, most flexible mixed-signal solution for high-speed digital debug and evaluation. With 12.5 GS/s digital sampling rate on 18 input channels, and the revolutionary QuickLink probing solution allowing seamless transitions from digital to high-bandwidth analog acquisitions, validation of challenging interfaces such as DDR4 has never been simpler or more comprehensive.

Complete Embedded System Debug

Modern embedded systems increasingly utilize high-speed digital buses, posing new and evolving challenges to validation and debug engineers. While analog signal-integrity characterization is a critical part of this process, the ability to decode and trigger on related digital buses is becoming a vital capability. The HDA125 High-speed Digital Analyzer addresses this need with the most flexible solution available.

Unique probing solution

One of the most challenging aspects of high-speed embedded test is simply getting the signals from the system under test to the instrumentation with sufficient fidelity. The HDA125 is built around Teledyne LeCroy's revolutionary QuickLink probing concept - enabling high signal quality, easy access to remote test points, and simple transitions from digital to analog probing.

Enhanced DDR Debug

Teledyne LeCroy already offers the industry's only dedicated DDR Debug Toolkit, designed to simplify challenging memory interface validation. Adding the HDA125 allows the DDR command bus to be directly acquired and integrated into the analysis, enabling advanced command triggering and sophisticated, searchable bus state viewing.

STANDARD SPECIFIC SOLUTIONS



The SDA 8Zi-B is configured specifically for testing serial data signals. With high-speed serial triggering capability and the most comprehensive analysis software, the SDA 8Zi-B is the obvious choice for the most challenging test and debug tasks:

DDR Memory

Verifying DDR memory operation is one of the most common challenges in high-speed electronics today. The SDA 8Zi-B is the ideal platform for validating and debugging DDR implementations.

- Teledyne LeCroy's unique DDR Debug toolkit is the ultimate DDR analysis package. Perform Read/Write burst separation and display eye diagrams, jitter analysis, and measurements specific to DDR, allowing for a quick understanding of system performance with a push of a button.
- QualiPHY-DDR packages perform automated JEDEC compliance testing for DDR2, DDR3, DDR4, LPDDR2, and LPDDR3.
- Unique probing solutions solve the challenge of probing DDR signals.

PCI Express®

The SDA 8Zi-B is the basis of the industry's most complete PCI Express test solution:

- Automated transmitter and receiver compliance testing using QualiPHY.
- The only certified solution for Link Equalization testing (required for PCI-SIG compliance) using the PeRT³ Phoenix.
- Comprehensive PCIe debug capability:
 - SDAIII eye and jitter analysis with built-in PCIe clock recovery emulation and eye masks
 - Protocol-layer decode correlated to physical-layer traces
 - PCle-specific measurements.

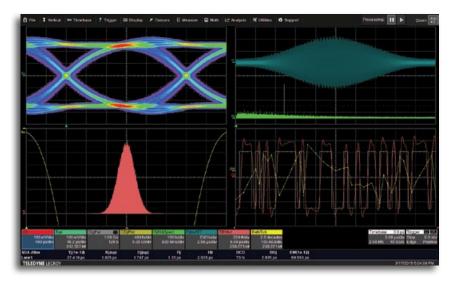
Automated Compliance Testing

Teledyne LeCroy's QualiPHY software is the ideal solution for physical layer compliance testing, making it easy to produce a comprehensive report of test results including screenshots. QualiPHY reduces the time and effort needed to perform compliance testing on a wide array of serial standards including:

- PCI Express (1.0, 2.0, 3.0)
- USB1, USB2, USB 3.0, USB 3.1
- DDR2, LPDDR2, DDR3, LPDDR3, DDR4
- SAS2, SAS3, SATA
- MIPI D-PHY and M-PHY
- 10/100/100 BASE-T,
 10GBASE-T,
 10GBASE-KR, SFI
- HDMI 1.4, HDMI 2.0, DisplayPort, eDP
 - MOST50, MOST150, BroadR-Reach



SDAIII CORE SERIAL DATA ANALYSIS TOOLKIT



The Teledyne LeCroy SDAIII-CompleteLinQ
Serial Data Analysis products include multilane eye and jitter analysis, LaneScape™ comparison modes, vertical noise measurements, and crosstalk analysis tools. These capabilities provide the deepest insight into the behavior of multi- or single-lane serial data systems.

SDAIII Core Toolset

Teledyne LeCroy provides the most complete toolset in the industry for jitter measurements and eye diagram/jitter analysis. Rj and Dj are separated and Dj is decomposed using one of three dual-dirac algorithms. Eye diagrams

Recommended

containing all acquired unit intervals are rendered 10-100x faster than competitive systems. Eye diagram analysis tools, such as the extrapolated IsoBER plot, aid insight. Multiple additional tools, such as Tracks, Histograms, and Spectrum waveforms, enhance the understanding of jitter causes. Sophisticated pattern analysis tools like Intersymbol Interference (ISI) measurements and plots provide deep insight into Data Dependent Jitter (DDj) behavior.

Data Rate Configuration Chart

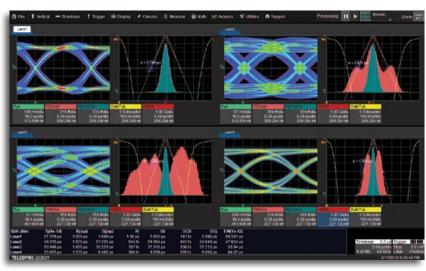
Minimum

Standard	Bit Rate	Mınımum Bandwidth	Recommended Oscilloscope
PCI Express Gen1	2.5 Gb/s	6 GHz	SDA 806Zi-B or Above
InfiniBand	2.5 Gb/s		
Serial Rapid I/O	2.5 Gb/s		
DisplayPort 1.1	2.7 Gb/s	0.011	
SAS Gen1	3 Gb/s	8 GHz	SDA 808Zi-B or Above
Serial Rapid I/O	3.125 Gb/s		
XAUI	3.125 Gb/s		
HDMI 1.4	3.4 Gb/s		
SATA Gen2	3 Gb/s	10.011	
DDR4	4 GT/s	10 GHz	
Fibre Channel 4GFC	4.25 Gb/s		
Serial Rapid I/O	4.25 Gb/s		
InfiniBand	5 Gb/s		ODA 0107: D Ab
PCI Express Gen2	5 Gb/s	13 GHz	SDA 813Zi-B or Above
PCI Express Gen3	8 Gb/s		
Serial Rapid I/O	5 Gb/s		
USB 3.0	5 Gb/s		
DisplayPort 1.2	5.4 Gb/s		
GDDR5	6 Gb/s		
SAS Gen2	6 Gb/s		
SATA Gen3	6 Gb/s	16.011-	SDA 816Zi-B or Above
Serial Rapid I/O	6.25 Gb/s	16 GHz	SDA 810ZI-B OF Above
QPI (Quick Path Interconnect)	6.4 Gb/s		
USB 3.1	10 Gb/s		
10GBase-KR	10.3125 Gb/s	00.011-	ODA 0007: D Ab
SFI/SFP+	10.3125 Gb/s	20 GHz	SDA 820Zi-B or Above
CEI-11	11 Gbps	25 CU-	CDA 9257i B or Above
SAS12	12 Gb/s	25 GHz	SDA 825Zi-B or Above
InfiniBand	25.78125 Gb/s		SDA 830Zi-B,
CEI-25/28	25-28 Gb/s	30 to 100 GHz	LabMaster 9 Zi-B or LabMaster 10 Zi up to 100 GHz

SDAIII UPGRADES AND SDAIII-COMPLETELINQ

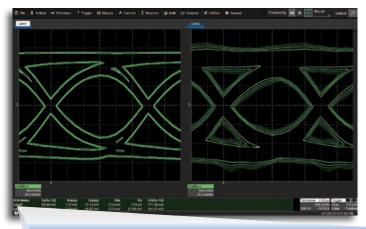
Measure up to 4 Lanes Simultaneously

"LinQ" products provide extensive multi-lane analysis capabilities. Quickly understand lane-to-lane differences in jitter measurements, eye diagrams, and jitter analysis. Perform aggressor on/off analysis, and see the results from both scenarios simultaneously. Save the analysis of a particular scenario to the Reference Lane, and configure a LaneScape™ Comparison mode to compare the Reference to either one, two or all lanes. Each "lane" can be a different serial data lane, or a different analysis of data from a single serial data lane - ideal for comparing different equalization schemes (using Eye Doctor II option) or examining system behaviors at different locations in the link (using probes or the VirtualProbe option).



Vertical Noise and Crosstalk

The Crosstalk and CrossLinQ packages provide vertical noise measurements and crosstalk analysis tools for



complete aggressor/victim analysis. Use one of three dual-Dirac models to measure and separate noise into total (Tn), random (Rn) and deterministic (Dn) components, and further decompose Dn into Intersymbol Interference Noise (ISIn) and Periodic Noise (Pn). Only Teledyne LeCroy performs this analysis on real-time oscilloscopes. Similar to jitter analysis, noise can be viewed as a noise track, histogram and spectrum, providing insight into the vertical noise resulting from coupling to other active serial data lanes or other interference sources. The Crosstalk Eye shows the probabilistic extent of noise both inside and outside the eye, quickly showing the impact of excessive noise that is not possible to see in a traditional eye diagram.

SDA Noise	Tn(1e-12)	Rn(sp)	Dn(sp)	ISIn	Pn
Lane1	65.94 mV	1.32 mV	47.41 mV	12.9 mV	214 µV
Lane2	96.52 mV	3.59 mV	45.97 mV	12.9 mV	13.69 mV

Learn More: teledynelecroy.com/SDAIII

CompleteLinQ Does it All

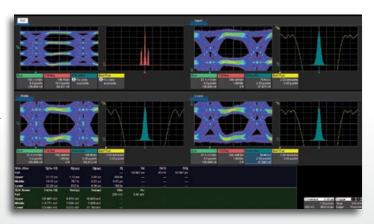
The CompleteLinQ user interface framework provides easy access to all features described above, and also integrates EyeDoctorII and VirtualProbe capabilities for Tx/Rx equalization and fixture/channel de-embedding/emulation. Order SDAIII-CompleteLinQ to equip your oscilloscope with all of Teledyne LeCroy's Serial Data Analysis and Signal Integrity tools.



ADVANCED SERIAL DATA AND SIGNAL INTEGRITY TOOLS

PAM4 Signal Analysis

Teledyne LeCroy's PAM4 analysis package builds on SDAIII's industry-leading eye, jitter and noise analysis technology to perform a complete analysis of all three eye openings in a PAM4 signal. Measurements for each opening include: Eye Height, Width Tj, Rj, Dj, Tn, Rn and Dn. Mean and RMS vales for each level are also determined, as well as periodic noise and jitter results. Enhance understanding of PAM4 signal behavior by displaying histograms, spectra, bathtub and IsoBER curves for each eye opening. PAM4 analysis is compatible with EyeDoctorII, allowing users to de-embed channel and fixture effects, emulate a channel, or apply equalization.



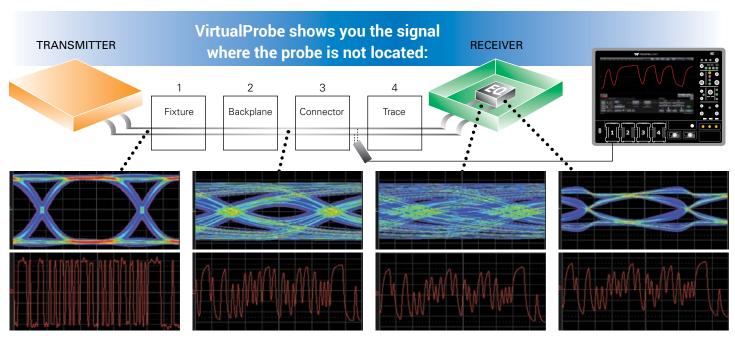
Advanced Signal Integrity Tools

EyeDoctorII

Many high-speed measurements require removing the effects of a fixture, applying a channel model, and emulating the operation of a receiver equalizer on an acquired signal. The EyeDoctorII package includes easy configuration of basic de-embed/emulation scenarios, CTLE, DFE and FFE equalizers, and transmitter emphasis/de-emphasis.

VirtualProbe

The VirtualProbe package expands the capabilities of EyeDoctorII. Configure a multi-block circuit using S-parameters, and VirtualProbe will display the signal as it would appear before or after any block in the circuit. The electrical behavior of a block to reflect and transmit signals can be included, added or removed. Probe loading effects can also be removed.



Virtually probe the signal at the transmitter with the fixture present, and then de-embed its effects form the measurement.

View the signal between structures to understand losses, ISI and crosstalk caused by backplanes, interconnects and connectors.

See what the eye looks like at the receiver - even if it is not in reach of a differential probe.

Use EyeDoctor to open the eye by modeling CTLE, FFE and DFE equalizers used by your receiver.

A COMPLETE SERIAL DATA TEST SUITE

Modern high-speed electronics test demands a set of instruments that goes beyond the oscilloscope, for applications such as receiver tolerance testing and interconnect characterization. Teledyne LeCroy addresses these challenges with innovative instruments which are both powerful and easy to use, simplifying test and reducing time-to-market.

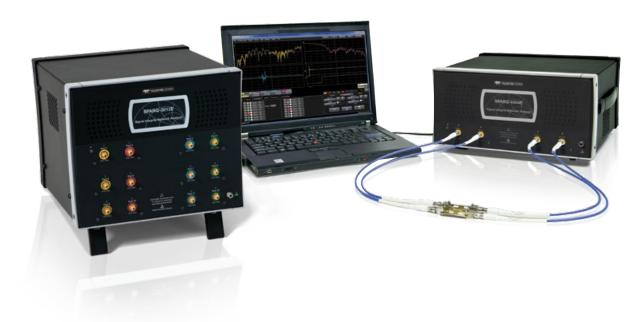
PeRT³ Phoenix – Protocol Enabled Receiver and Transmitter Tolerance Tester

Modern serial data standards such as PCI Express 3.0 require negotiation of equalization parameters to ensure interoperability. Truly testing a receiver's operation demands an instrument which perform more than just the basic BERT functions of pattern generation and error detection. Teledyne LeCroy's PeRT³ is the industry's first Protocol-enabled Receiver Tester, a totally new class of instrument designed to overcome these difficult test challenges. The combination of the PeRT³ and the SDA 8Zi-B represents the most complete serial data test system available.



SPARQ Signal Integrity Network Analyzer

The SPARQ series of signal integrity network analyzers make S-parameter measurements on up to 12 ports and to 30 GHz (40 GHz for 4 port models). SPARQ uses the industry's only built-in and automatic OSLT calibration methodology. Users simply connect their SPARQ to their DUT and their PC to the SPARQ via USB. When making a measurement, the OSLT calibration proceeds automatically and without any requirement for the user intervention for the calibration or to switch the connections to the DUT. This "hands-off" approach allows high-frequency S-parameters to be measured by any engineer and without the need for "VNA expertise". SPARQ is the ideal instrument for characterizing multi-port interconnects common in signal integrity applications at a fraction of the cost of traditional methods. With 8 and 12 port SPARQs, measurements can be made for less cost than a similar 4-port VNA, allowing users to easily and quickly make crosstalk measurements on 2 or 3 lane interconnects.



WAVELINK PROBE SYSTEMS

WaveLink High Bandwidth Differential Probes

Ultra-wideband Architecture with Superior Signal Fidelity

Teledyne LeCroy's WaveLink® high bandwidth differential probes utilize advanced amplifier architecture to achieve superior analog broadband performance. Exceptional noise characteristics mean the combination of the probe and the oscilloscope results in measurement performance that is nearly identical to that of a cable input.

Versatile High Bandwidth Probe Tips up to 25 GHz

Solder-In tips with 25 GHz bandwidth and system (probe + oscilloscope) rise times equal to that of the oscilloscope alone. The most compact positioner tip browser with bandwidth up to 22 GHz makes probing in confined areas easy.

Superior Probe Impedance Minimizes Circuit Loading

Circuit and signal loading is reduced by more than 50% compared to competitive probes. In the mid-band frequency range, the difference is even more apparent.



D2505-A-PS 25 GHz probe system with Solder-In lead and browser positioner tip.

	D1305-A-PS	D1605-A-PS	D2005-A-PS	D2505-A-PS
Bandwidth	Dxx05-SI and Dxx05-PT Tips 13 GHz	Dxx05-SI and Dxx05-PT Tips 16 GHz	Dxx05-SI and Dxx05-PT Tips 20 GHz	Dxx05-SI Lead 25 GHz
	10 0112	10 0112	20 0112	Dxx05-PT Tip
				22 GHz typical
				20 GHz guaranteed
Rise Time (10-90%)	Dxx05-SI and	Dxx05-SI and	Dxx05-SI and	Dxx05-SI Lead
	Dxx05-PT Tips	Dxx05-PT Tips	Dxx05-PT Tips	17.5 ps (typical)
	32.5 ps (typical)	28 ps (typical)	20 ps (typical)	DOF DT Ti-
				Dxx05-PT Tip 19 ps (typical)
D: T: (00 00%)	D 05 01 1	D 05 01 1	D 05 01 1	
Rise Time (20-80%)	Dxx05-SI and	Dxx05-SI and	Dxx05-SI and	Dxx05-SI Lead
	Dxx05-PT Tips	Dxx05-PT Tips	Dxx05-PT Tips	13 ps (typical)
	24.5 ps (typical)	21 ps (typical)	15 ps (typical)	Dxx05-PT Tip
				14 ps (typical)
Noise (Probe)	< 14 nV/√Hz	< 14 nV/√Hz	< 18 nV/√Hz	< 18 nV/√Hz
	(1.6 mV _{rms})	(1.8 mV _{rms})	(2.5 mV _{rms})	(2.8 mV _{rms})
	(typical)	(typical)	(typical)	(typical)
Input Dynamic Range		2.0 V _{pk-pk} , (±1	.0 V) (nominal)	
Input Common Mode			nominal)	
Voltage Range				
Input Offset Voltage Range		±2.5 V Differe	ential (nominal)	
Impedance	Dx	x 05-SI Lead: 300 Ω a	t 6 GHz, 525 Ω at 13	GHz,
(mid-band, typical)	600	Ω at 16 GHz, 300 Ω a	at 20 GHz, 120 Ω at 2	5 GHz

Dxx05-PT Tip: 160 Ω at 6 GHz, 450 Ω at 13 GHz, 240 Ω at 16 GHz, 210 Ω at 20 GHz

Other WaveLink Probing Solutions

With bandwidths from 4 GHz to 13 GHz, wide input dynamic range, exceptionally low loading and versatile tip selections, the Medium- and Low Bandwidth WaveLink Differential Probe Systems are ideal for many applications - including the oftenchallenging probing of DDR memory signals.

WaveLink Low Bandwidth Differential Probes

- 4 and 6 GHz models
- Solder-In, Browser, Quick Connect, Square Pin, Positioner Tip, QuickLink adapter and HiTemp Cables



WaveLink Medium Bandwidth Differential Probes

- 8.10. and 13 GHz models
- 3.5 V_{p-n} Input Dynamic Range
- ±4 V Offset
- Solder-in, Positioner (Browser), Square Pin, QuickLink adapter, Hi-Temp cables, and SMA/SMP lead connection



BROAD RANGE OF PROBING SOLUTIONS

WaveMaster 8 Zi-B oscilloscopes support a broad range of probes for a variety of applications.

ZS Series High Impedance Active Probes

- 1 GHz (ZS1000), 1.5 GHz (ZS1500) and 2.5 GHz (ZS2500) bandwidths
- High Impedance (0.9 pF, 1 M Ω)
- Extensive standard and available probe tip and ground connection accessories
- ±12 Vdc offset (ZS1500)
- Teledyne LeCroy ProBus system



High-Voltage Differential Probes

- 20 MHz and 100 MHz bandwidth
- 1,000 V_{ms} common mode voltage
- 1,400 V_{peak} differential voltage
- EN 61010 CAT III
- 80 dB CMRR at 50/60 Hz
- Teledyne LeCroy ProBus system

High-Voltage Passive Probes

- Suitable for safe, accurate high-voltage measurements
- Fixed-attenuation probes covering a range from 1 kV to 6 kV and varying transient overvoltage ratings



• Works with any 1 M Ω input oscilloscope

Current Probes

- Range of probes from 30 A_{rms} (50 A_{peak}) to 500 A_{rms} (700 A_{peak})
- 2 MHz to 100 MHz bandwidths
- Small form factor accommodates large conductors with small jaw size
- Teledyne LeCroy ProBus system



ZD Series Differential Probes

- 200 MHz, 500 MHz, 1 GHz and 1.5 GHz bandwidths
- Wide range of probing accessories
- Teledyne LeCroy ProBus system



Optical-to-Electrical Converter (OE695G)

- Reference receiver support from 8GFC to 10GFC FC, or Custom (up to 12.5 Gb/s)
- Frequency range DC to 9.5
 GHz (electrical, -3 dB)
- 62.5/125 μm multi-mode or single-mode fiber input
- Broad wavelength range (750 to 1650 nm)
- +7 dBm (5 mW) max peak optical power
- Low noise (as low as 25 pW/√Hz)





2 GS/s Mixed Signal Oscilloscope Options (MS-250/MS-500)

The Mixed Signal options allow the WaveMaster 8 Zi-B to operate as a mixed signal oscilloscope with up to 36 digital channels with 2 GS/s digital sample rate and 50 Mpts/Ch.

Vertical System	WaveMaster 804Zi-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster 808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
Analog Bandwidth	4 GHz	6 GHz	8 GHz	13 GHz
@ 50 Ω (-3 dB)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)
(ProLink Input)				
Analog Bandwidth	3.5 GHz	3.5 GHz	3.5 GHz	3.5 GHz
@ 50 Ω (-3 dB) (ProBus Input)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)
Analog Bandwidth @ 1 MΩ (-3 dB) (ProBus Input)	500 MHz (typical, ≥ 2 mV/div)			
Rise Time	95 ps	63 ps	49 ps	32.5 ps
(10-90%, 50 Ω)	(test limit,	(test limit,	(test limit,	(test limit,
	flatness mode)	flatness mode)	flatness mode)	flatness mode)
Rise Time	71 ps	47 ps	37 ps	24.5 ps
(20-80%, 50 Ω)	(flatness mode)	(flatness mode)	(flatness mode)	(flatness mode)
Input Channels	4 (Any combination of ProLink	and ProBus inputs)		
Bandwidth Limiters	20 MHz, 200 MHz,	20 MHz, 200 MHz,	20 MHz, 200 MHz,	20 MHz, 200 MHz,
	1 GHz	1 GHz, 4 GHz	1 GHz, 4 GHz,	1 GHz, 4 GHz,
			6 GHz	6 GHz, 8 GHz
Input Impedance	ProLink Inputs: $50 \Omega \pm 2\%$ for \leq	100 mV/div, 50 Ω ±3% for > 100) mV/div	
	ProBus Inputs: $50 \Omega \pm 2\%$ or 1 l	M Ω 16 pF, 1 M Ω 11 pF with s	upplied Probe	
Input Coupling	ProLink Inputs: 50 Ω : DC, GND			
	ProBus Inputs: 1 M Ω : AC, DC, 0	SND; 50 Ω : DC, GND		
Maximum Input Voltage	50 Ω (ProLink) : ±2 V max. @ ≤	100 mV/div, 5.5 V _{rms} @ > 100 m	nV/div	
	50 Ω (ProBus): ±5 V max., 3.5 \			
	1 MΩ (ProBus): 250 V max. (pe	eak AC: < 10 kHz + DC)		
Channel-Channel	DC to 10 GHz: 50 dB (> 315:1)			
Isolation	10 to 15 GHz: 46 dB (> 200:1)			
	15 to 20 GHz : 40 dB (> 100:1)	anala aana ar different wish	ttings typical)	
	(For any two ProLink input chai	nnels, same or different v/div se	tungs, typicai)	
	015	(5250)		
Vertical Resolution	8 bits up to 11 bits with enhance	cea resolution (ERES)		

Vertical System	WaveMaster 816Zi-B (SDA)	WaveMaster 820Zi-B (SDA, DDA)	WaveMaster 825Zi-B (SDA)	WaveMaster 830Zi-B (SDA)
Analog Bandwidth @ 50 Ω (-3 dB) (2.92 mm input)			25 GHz	30 GHz
Analog Bandwidth @ 50 Ω (-3 dB) (ProLink Input)	16 GHz (≥ 10 mV/div)	20 GHz (≥ 10 mV/div)	20 GHz (≥ 10 mV/div)	20 GHz (≥ 10 mV/div)
Analog Bandwidth @ 50 Ω (-3 dB) (ProBus Input)	3.5 GHz (≥ 10 mV/div)	3.5 GHz (≥ 10 mV/div)	3.5 GHz (≥ 10 mV/div)	3.5 GHz (≥ 10 mV/div)
Analog Bandwidth @ 1 MΩ (-3 dB) (ProBus Input)	500 MHz (typical, ≥ 2 mV/div)			
Rise Time (10-90%, 50 Ω)	28.5 ps (test limit, flatness mode)	22 ps (test limit, flatness mode)	17.5 ps (test limit, flatness mode)	15.5 ps (test limit, flatness mode)
Rise Time (20–80%, 50 Ω)	21.5 ps (flatness mode)	16.5 ps (flatness mode)	13 ps (flatness mode)	11.5 ps (flatness mode)
Input Channels	4 (Any combination of Pr	oLink and ProBus inputs)	4 (Any combina ProLink inputs or 3.5 3 (1 @ full BW, 2 with ProLink o	
Bandwidth Limiters	40 GS/s mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz 80 GS/s Mode: 13 GHz	40 GS/s mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz, 16 GHz 80 GS/s Mode: 13 GHz, 16 GHz	For ≤ 20 GHz Mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz, 16 GHz For > 20 GHz Mode: 20 GHz	For ≤ 20 GHz Mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz, 16 GHz For > 20 GHz Mode: 20 GHz, 25 GHz
Input Impedance	$50 \Omega \pm 2\%$ for $\leq 100 \text{ mV/div}$, ProBus	k Inputs: $50 \Omega \pm 3\%$ for > 100 mV/div liputs: $\Omega \parallel 11$ pF with supplied Probe	ProBus	n Inputs: $50 \Omega \pm 3\%$ for > 79 mV/div Inputs: $50 \Omega \pm 3\%$ for > 100 mV/div
Input Coupling	50 Ω : D	k Inputs: DC, GND Inputs: ID; 50 Ω: DC, GND	2.92 mn 50 Ω: D ProLink	n Inputs: C, GND Inputs: C, GND Inputs:
Maximum Input Voltage	±2 V max. @ ≤ 100 mV/div 50 Ω (F ±5 V max 1 MΩ (F	ProLink): v, 5.5 V _{rms} @ > 100 mV/div ProBus): , 3.5 V _{rms} ProBus): AC: < 10 kHz + DC)	2.92 mn ±2 Vmax @ ≤ 100 mV/div 50 Ω (P ±2 Vmax @ ≤ 100 mV/div	n Inputs: , 5.5 V _{rms} @ > 100 mV/div roLink): , 5.5 V _{rms} @ > 100 mV/div roBus): , 3.5 V _{rms} ProBus):
Channel-Channel Isolation Vertical Resolution	10 to 15 GHz: 15 to 20 GHz: (For any two ProLink in	50 dB (> 315:1) 46 dB (> 200:1) 40 dB (> 100:1) nput channels, same or settings, typical)	DC to 10 GHz: 10 to 15 GHz: 15 to 20 GHz: 20 GHz to Max B (For any two ProLink or 2.92 different v/div s	46 dB (> 200:1) 40 dB (> 100:1) W: 30 dB (> 32:1) mm input channels, same or

Vertical System WaveMaster **WaveMaster** WaveMaster WaveMaster 808Zi-B (SDA/DDA) (cont'd) 813Zi-B (SDA) 804Zi-B (SDA) 806Zi-B (SDA/DDA) Sensitivity **50** Ω (ProLink): 2 mV-1 V/div. fully variable (2-9.9 mV/div via zoom) **50** Ω (ProBus): 2 mV-1 V/div, fully variable 1 M Ω (ProBus): 2 mV-10 V/div, fully variable DC Vertical Gain Accuracy ±1% F.S. (typical), offset at 0 V; ±1.5% F.S. (test limit), offset at 0 V (Gain Component of DC Accuracy) Vertical Noise Floor $0.75\,\mathrm{mV}_{\mathrm{rms}}$ 0.93 mV_{rms} $1.05\,\mathrm{mV}_{\mathrm{rms}}$ 1.21 mV_{rms} (50 mV/div) (typical) (typical) (typical) (typical) Offset Range 50 Ω (ProLink): ±500 mV @ 2-100 mV/div ±4 V @ > 100 mV/div-1 V/div 50 Ω (ProBus): ±750 mV @ 2-100 mV/div ±4 V @ > 100 mV/div-1 V/div 1 M Ω : ±1 V @ 2-140 mV/div ±10 V @ 142 mV-1.40 V/div ±100 V @ 1.42 V-10 V/div DC Vertical Offset Accuracy ±(1.5% of offset setting + 1.5% F.S. + 1 mV) (test limit) **Horizontal System** Timebases Internal time base common to 4 input channels 20 ps/div-128 s/div, depending on memory length Time/Division Range Real-time Mode: 20 ps/div-64 s/div; RIS Mode: 20 ps/div-10 ns/div: user selectable at ≤ 10 ns/div: Roll Mode: 100 ms/div up to 128 s/div, user selectable at ≥ 100 ms/div and ≤ 5 MS/s Clock Accuracy < 1 ppm + (aging of 0.5 ppm/yr from last calibration) Sample Clock Jitter Up to 10µs Acquired Time Range: 100 fsrms (Internal Timebase Reference) Up to 6.4ms Acquired Time Range: 150 fsrms (Internal Timebase Reference) Delta Time Noise Measurement Accuracy $\sqrt{2}$ (Sample Clock Jitter_{rms}) 2 + (clock accuracy * reading) Jitter Measurement Floor (Sample Clock Jitter_{rms})² SlewRate <450 fs_{rms} <425 fs_{rms} <325 fs_{rms} <500 fs_{rms} Jitter Between Channels (TIE, typical, measured at maximum bandwidth) Trigger and < 0.1 ps_{rms} (typical, software assisted), 2 ps_{rms} (typical, hardware) Interpolator Jitter

±9 x time/div. setting or 25 ns max. (whichever is larger), each channel

10 MHz; 50 Ω impedance, applied at the rear input

10 MHz; 50 Ω impedance, output at the rear

Channel-Channel

Reference (Input)

External Time base

Reference (Output)

Deskew Range External Time base

Vertical System (cont'd)	WaveMaster 816Zi-B (SDA)	WaveMaster 820Zi-B (SDA, DDA)	WaveMaster 825Zi-B (SDA)	WaveMaster 830Zi-B (SDA)
Sensitivity	(2-9.9 mV/c 50 Ω (ProLink) at 80 GS/s : (2-19.9 mV/ 50 Ω (ProBus): 2 mV	: 2 mV-1 V/div, fully variable div via zoom) : 2 mV-1 V/div, fully variable div via zoom) (-1 V/div, fully variable -10 V/div, fully variable	10 mV−500 mV 50 Ω (F 2 mV−1 V/div, fully variab 50 Ω (F 2 mV−1 V/div 1 M Ω (92 mm): /div, fully variable ProLink): le (2-9.9 mV/div via zoom) ProBus): v, fully variable ProBus) v, fully variable
DC Vertical Gain Accuracy Gain Component of DC Accuracy)	±1% F.S. (typical), offset at 0 V;	±1.5% F.S. (test limit), offset at 0	V	
Vertical Noise Floor (50 mV/div)	1.28 mV _{rms} (typical)	1.44 mV _{rms} (typical)	1.88 mV _{rms} (typical)	2.12 mV _{rms} (typical)
Offset Range	±500 mV @ 2 ±4 V @ > 100 u 50 \(\Omega\) (F ±750 mV @ 2 ±4 V @ > 100 u ±1 V @ 2- ±10 V @ 142 u	ProLink): 2-100 mV/div mV/div-1 V/div ProBus): 2-100 mV/div mV/div-1 V/div MΩ: 140 mV/div mV-1.40 V/div 42 V-10 V/div	±500 mV @ 5 ±4 V @ 80 mV/ 50 Q (F ±500 mV @ 2 ±4 V @ >100 r 50 Q (F ±750 mV @ 2 ±4 V @ >100 r	P2 mm): 10-79 mV/div div-500 mV/div ProLink): 2-100 mV/div nV/div-1 V/div ProBus): 2-100 mV/div nV/div-1 V/div MΩ: 128 mV/div

Horizontal System

Timebases	Internal time base common to 4 input channels	
Time/Division Range	Real-time Mode at 80 GS/s: 20 ps/div-640 µs/div, depending on memory length Real-time Mode at other sample rates: 20 ps/div-128 s/div, depending on memory length Real-time Mode: 20 ps/div-64 s/div; RIS Mode: 20 ps/div-10 ns/div; user selectable at ≤ 10 ns/div; Roll Mode: 100 ms/div up to 128 s/div, user selectable at ≥ 100	For ≥ 25 GHz Mode: Real-time Mode: 20 ps/div-640 µs/div, depending on memory length For ≤ 20 GHz Mode: 20 ps/div-128 s/div, depending on memory length Real-time Mode: 20 ps/div-64 s/div; RIS Mode: 20 ps/div-10 ns/div, user selectable at ≤10 ns/div;
	ms/div and ≤ 5 MS/s	Roll Mode: 100 ms/div up to 128 s/div, user selectable at ≥ 100 ms/div and ≤ 5 MS/s
Clock Accuracy	< 1 ppm + (aging of 0.5 ppm/yr from last calibration)	
Sample Clock Jitter	Up to 10µs Acquired Time Range: 100 fsrms (Internal Timebase Up to 6.4ms Acquired Time Range: 150 fsrms (Internal Timebase	
Delta Time Measurement Accuracy	$\sqrt{2} * \sqrt{\frac{\text{Noise}}{\text{SlewRate}}}^2 + (\text{Sample Clock Jitter}_{rms})^2 + (6)$	clock accuracy * reading)
Jitter Measurement Floor	$\sqrt{\left(\frac{\text{Noise}}{\text{SlewRate}}\right)^2 + (\text{Sample Clock Jitter}_{rms})^2}$	
Jitter Between Channels (TIE, typical, measured at maximum bandwidth)		<250 fs _{rms}
Trigger and Interpolator Jitter	< 0.1 ps _{rms} (typical, software assisted), 2 ps _{rms} (typical, hardware	re)
Channel-Channel Deskew Range	±9 x time/div. setting or 25 ns max. (whichever is larger), each c	hannel
External Time base Reference (Input)	10 MHz; 50 Ω impedance, applied at the rear input	
External Time base Reference (Output)	10 MHz; 50 Ω impedance, output at the rear	

	M	-14	W	Maria Maria da m	M M A
Acquisition System		eMaster i-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster 808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
Single-Shot	40 GS/s on 4	Ch	· · · · · · · · · · · · · · · · · · ·		
Sample Rate/Ch	(80 GS/s on 2	? Ch using optional	WM8Zi-2X80GS External Interle	eaving Device)	
Random Interleaved Sampling (RIS)	200 GS/s for	repetitive signals (20 ps/div to 10 ns/div)		
Maximum Trigger Rate	1,000,000 wa	veforms/second (i	in Sequence Mode, up to 4 chan	nels)	
Intersegment Time	1 μs				
Maximum Acquisition Memory	256 Mpts/Ch				
Standard Memory	SDA models: DDA models:	32 Mpts, 5,000 se 64 Mpts, 15,000 se 128 Mpts, 15,000	egments max segments max	ith use of WM8Zi-2X80GS Externa	al Interleaving Device)
Memory Options	(Wernory are	Carriple riate carr	Max	THE THE STATE OF WINDER EXCERNA	in interieuving bevice)
	Option	Mem/Ch	Segments		
	M-64	64 Mpts	15,000		
	L-128	128 Mpts	15,000		
	VL-256	256 Mpts	15,000		
	(Memory and	Sample Rate can	be doubled in 1 or 2 Ch mode w	ith use of WM8Zi-2X80GS Externa	al Interleaving Device)
Acquisition Processin	na .				
Averaging		raging to 1 million	sweeps continuous averaging to	1 million sweeps	
Enhanced Resolution (ERES)		1 bits vertical reso		·	
Envelope (Extrema)	Envelope, floo	or, or roof for up to	1 million sweeps		
Interpolation	Linear or Sin	x/x			
Triggering System					
Modes	Normal, Auto	Single, and Stop			

(LITEO)				
Envelope (Extrema)	Envelope, floor, or roof for up to	1 million sweeps		
Interpolation	Linear or Sin x/x			
Triggering System				
Modes	Normal, Auto, Single, and Stop			
Sources	Any input channel, Aux, Aux/10,	Line, or Fast Edge. Slope and lev	vel unique to each source (excep	t line trigger)
Coupling Mode	DC, AC, HFRej, LFRej			
Pre-trigger Delay	0-100% of memory size (adjust	table in 1% increments of 100 ns	8)	
Post-trigger Delay	0–10,000 divisions in real time	mode, limited at slower time/div	settings or in roll mode	
Hold-off by Time	From 2 ns up to 20 s or from 1 t	o 99,999,999 events		
or Events				
Internal Trigger Range	±4.1 div from center			
Trigger Sensitivity	Not Applicable			
with Edge Trigger 2.92mm Inputs				
2.9211111 IIIputs				
Trigger Sensitivity	2 div @ < 3.5 GHz			
with Edge Trigger	1.5 div @ < 1.75 GHz			
(Ch 1-4) ProBus Inputs	1.0 div @ < 200 MHz			
	(for DC coupling, ≥ 10 mV/div, 5			
Trigger Sensitivity	2 div @ < 4 GHz,	2 div @ < 6 GHz	2 div @ < 8 GHz	3 div @ < 13 GHz
with Edge Trigger	1.5 div @ < 3 GHz,	1.5 div @ < 3 GHz	1.5 div @ < 3 GHz	1.5 div @ < 3 GHz
(Ch 1-4)	1.0 div @ < 200 MHz,	1.0 div @ < 200 MHz	1.0 div @ < 200 MHz	1.0 div @ < 200 MHz
ProLink Inputs	(for DC, AC, LFRej coupling,	(for DC, AC, LFRej coupling,	(for DC, AC, LFRej coupling,	(for DC, AC, LFRej coupling,
	≥ 10 mV/div, 50 Ω)	≥ 10 mV/div, 50 Ω)	≥ 10 mV/div, 50 Ω)	≥ 10 mV/div, 50 Ω)
	2 10 111 v / aiv, 00 32)	_ 10111v/ div, 00 <u>ua</u>)	_ 10111v/div, 00 ±2)	_ 10 111V/ div, 00 12)

Acquisition System	WaveMaste 816Zi-B (SD		WaveMaste 320Zi-B (SDA, I			aveMaster SZi-B (SDA))	WaveN 830Zi-E	
Single-Shot		40 GS/s on 4 (Ch				40 GS/s on 4	l Ch	
Sample Rate/Ch		80 GS/s on 2	Ch		(80 G	S/s on 2 Ch	when operat	ed in ≥ 25 G	Hz Mode)
Random Interleaved	200 GS/s for repe	etitive signals (2	0 ps/div to 10 ns	s/div)		For ≥ 25 (GHz Mode: N	lot applicabl	е
Sampling (RIS)					For <		de: 200 GS/s ps/div to 10		e signals
Maximum Trigger Rate	1,000,000 waveforms	/second (in Seq	uence Mode, up	to 4 chanr	nels)				
Intersegment Time	1 μs								
Maximum Acquisition Memory	5121	Mpts/Ch (2 Ch o	peration)			512 M _l	pts/Ch (2 Ch	operation)	
Standard Memory	(SDA: 64 (DDA: 128 (SDA: 128	4 channels: pts, 5,000 segm Mpts, 15,000 se Mpts, 15,000 se 2 channels: Mpts, 15,000 se	egments max) egments max) egments max) egments max)			(SDA: 64 M (DDA: 128 N (SDA: 128 N	4 channels s, 5,000 segr pts, 15,000 s Apts, 15,000 2 channels Apts, 15,000	ments max segments m segments m s: segments m	nax) nax)
Memory Options	(DDA: 250	Mpts, 15,000 se	Max			`	Mpts, 15,000 Innels		innels
Memory options	Option	Mem/Ch	Segments			4 Cha		Z Cha	
	M-64	64 Mpts	15,000		Option	Mem/Ch	Max Segments	Mem/Ch	Max Segments
	L-128	128 Mpts	15,000		M-64	64 Mpts	15,000	128 Mpts	10,000
	VL-256	256 Mpts	15,000		L-128	128 Mpts	15,000	256 Mpts	15,000
	VL 200	200 Mpt3	10,000		VL-256	256 Mpts	15,000	512 Mpts	15,000

Acquisition Processing

Averaging	Summed averaging to 1 million	sweeps continuous averaging to	o 1 million sweeps
Enhanced Resolution (ERES)	From 8.5 to 11 bits vertical reso	lution	
Envelope (Extrema)	Envelope, floor, or roof for up to	1 million sweeps	
Interpolation	Linear or Sin x/x		
Triggering System			
Modes	Normal, Auto, Single, and Stop		
Sources	Any input channel, Aux, Aux/10,	Line, or Fast Edge. Slope and lev	vel unique to each source (except line trigger)
Coupling Mode	DC, AC, HFRej, LFRej		
Pre-trigger Delay	0-100% of memory size (adjus	table in 1% increments of 100 ns	3)
Post-trigger Delay	0-10,000 divisions in real time	mode, limited at slower time/div	settings or in roll mode
Hold-off by Time	From 2 ns up to 20 s or from 1 t	to 99,999,999 events	
or Events			
Internal Trigger Range	±4.1 div from center		
Trigger Sensitivity	Not Ap	plicable	3 div @ < 15 GHz
with Edge Trigger			1.5 div @ < 3 GHz
2.92mm Inputs			1.0 div @ < 200 MHz (for DC coupling, ≥ 10 mV/div, 50 Ω)
Trigger Sensitivity with	2 div @ < 3.5 GHz		
Edge Trigger	1.5 div @ < 1.75 GHz		
(Ch 1-4) ProBus Inputs	1.0 div @ < 200 MHz		
, ,	(for DC coupling,≥ 10 mV/div, 50	$\Omega(\Omega)$	
Trigger Sensitivity with	3 div @ < 13 GHz		3 div @ < 15 GHz
Edge Trigger	1.5 div @ < 3 GHz		1.5 div @ < 3 GHz
(Ch 1-4) ProLink Inputs	1.0 div @ < 200 MHz		1.0 div @< 200 MHz
	(for DC, AC,		(for DC, AC,
	LFRej coupling,		LFRej coupling,
	≥ 10 mV/div, 50 \(\Omega\)		≥ 10 mV/div, 50 Ω)

Triggering System (cont'd)	WaveMaster 804Zi-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster 808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
External Trigger	2 div @ < 1 GHz			
Sensitivity (Edge Trigger)	1.5 div @ < 500 MHz			
, , , , , , , , , , , , , , , , , , , ,	1.0 div @ < 200 MHz			
	(for DC, coupling)			
Max. Trigger Frequency,		num triggerable width 200 ps)		
SMART Trigger External Trigger	Aux (±0.4 V); Aux/10 (±4 V)			
Input Range	Aux (±0.4 v), Aux/10 (±4 v)			
Basic Triggers				
Edge		ope (positive, negative, or either) a		
Window	Triggers when signal exits a w	vindow defined by adjustable thres	holds	
TV-Composite Video		ectable line and field HDTV (720p, elds (1–8), Lines (up to 2000), Fra r Negative)		
SMART Triggers [™]				
State or Edge Qualified	selectable by time or events	only if a defined state or edge occu	·	
Qualified First		e, triggers repeatably on event B or at of the acquisition. Holdoff betwe		
Dropout		longer than selected time between		, evento
Pattern	Logic combination (AND NAN	D, OR, NOR) of 5 inputs (4 channel	s and external trigger input) Fach	source can be high low or
· accom				
	don't care. The High and Low i	evel can be selected independently	y. Triggers at start or end of the pa	ttern
SMART Triggers with E	J	evel can be selected independently	y. Triggers at start or end of the pa	ttem
SMART Triggers with E	Exclusion Technology			
Glitch	Exclusion Technology Triggers on positive or negative	ve glitches with widths selectable	as low as 200 ps to 20 s, or on into	ermittent faults
Glitch Width (Signal or Pattern)	Exclusion Technology Triggers on positive or negative, Triggers on positive, negative,	re glitches with widths selectable or both widths with widths selecta	as low as 200 ps to 20 s, or on into	ermittent faults
Glitch	Exclusion Technology Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s	as low as 200 ps to 20 s, or on inte ble as low as 200 ps to 20 s, or on	ermittent faults
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout	Exclusion Technology Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 selectate (or transition edge) has co	as low as 200 ps to 20 s, or on into ble as low as 200 ps to 20 s, or on ccurred on another source.	ermittent faults
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified)	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectabl Triggers on any source if a giv Holdoff between sources is 1	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 steen state (or transition edge) has consto 20 s, or 1 to 99,999,999 ever	as low as 200 ps to 20 s, or on into ble as low as 200 ps to 20 s, or on ccurred on another source. ts	ermittent faults intermittent faults
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectabl Triggers on any source if a giv Holdoff between sources is 1 Trigger on positive or negative	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 selectate or transition edge) has consisted to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits	as low as 200 ps to 20 s, or on into ble as low as 200 ps to 20 s, or on ccurred on another source. ts and two time limits. Select betwee	ermittent faults intermittent faults en 1 ns and 20 ns
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified)	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectabl Triggers on any source if a giv Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 steen state (or transition edge) has consto 20 s, or 1 to 99,999,999 ever	as low as 200 ps to 20 s, or on inte ble as low as 200 ps to 20 s, or on ccurred on another source. ts and two time limits. Select betwee dge limits between 1 ns and 20 ns	ermittent faults intermittent faults en 1 ns and 20 ns
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Seguence) T	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a given Holdoff between sources is 1. Trigger on positive or negative. Trigger on edge rates. Select I Trigger on intermittent faults in triggering.	ve glitches with widths selectable and or both widths with widths selectable between 1 ns and 20 selectable sensition edge) has consisted to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits simits for dV, dt, and slope. Select expressions are selected behavior	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on ccurred on another source. Its and two time limits. Select betweed dge limits between 1 ns and 20 ns or and triggering when that condit	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a given Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select I Trigger on intermittent faults I Triggering.	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 sten state (or transition edge) has consto 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select e	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on ccurred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Triggering when the condite the properties of the condite the co	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Seguence) T	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind	ve glitches with widths selectable and or both widths with widths selectable between 1 ns and 20 selectable for transition edge) has consisted to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select expressions to 20 specifying the expected behavior on "B" event. Or Arm on "A" event,	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on ccurred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Triger on "D" event	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Mea	ve glitches with widths selectable and sort both widths with widths selectable to between 1 ns and 20 selected selectable to select the state (or transition edge) has considered to some state (or transition edge) has considered to some state (or transition edge) has considered to solect the selected between the selected behavior on "B" event. Or Arm on "A" event, lifty on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I assurement): Edge, Window, Pattern	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a give Holdoff between sources is 1. Trigger on positive or negative. Trigger on edge rates. Select I Trigger on intermittent faults I Triggering. Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only.	ve glitches with widths selectable and sort both widths with widths selectable to between 1 ns and 20 selected selectable to select the state (or transition edge) has considered to some state (or transition edge) has considered to some state (or transition edge) has considered to solect the selected between the selected behavior on "B" event. Or Arm on "A" event, lifty on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I assurement): Edge, Window, Pattern	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Mea	ve glitches with widths selectable and provided by the selectable selectable selectable selectable between 1 ns and 20 selectable se	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg	ve glitches with widths selectable and provided by the selectable selectable selectable selectable between 1 ns and 20 selectable se	as low as 200 ps to 20 s, or on interplace ble as low as 200 ps to 20 s, or on a courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement (Logic), Width, Glitch, Interval, Dropout, Dropout	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on opout, or Measurement. Mea
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar	ve glitches with widths selectable and both widths with widths selectable or both widths with widths selectable between 1 ns and 20 select sensition edge) has considered by the selectation of the selecta	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement on (Logic), Width, Glitch, Interval, Dropout, or Measurement on (1ns to 20s) or number of events.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar	ve glitches with widths selectable and both widths with widths selectable to between 1 ns and 20 selectable ten state (or transition edge) has considered to state (or transition edge) has considered to select edge to state (or transition edge) has considered to select edge to	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement on (Logic), Width, Glitch, Interval, Dropout, or Measurement on (1ns to 20s) or number of events.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar Measurement trigger selection prior stage and the last stage.	ve glitches with widths selectable and both widths with widths selectable or both widths with widths selectable between 1 ns and 20 select sensition edge) has considered by the selectation of the selecta	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement on (Logic), Width, Glitch, Interval, Dropout, or Measurement on (1ns to 20s) or number of events.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea- an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff High-speed Serial Prof	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar Measurement trigger selection prior stage and the last stage.	ve glitches with widths selectable and both widths with widths selectable or both widths with widths selectable between 1 ns and 20 sometimes are state (or transition edge) has considered by the selectation of the selectat	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement on (Logic), Width, Glitch, Interval, Dropout, or Measurement on (1ns to 20s) or number of events.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff	Triggers on positive or negative. Triggers on positive, negative, Triggers on intervals selectabl. Triggers on any source if a giv. Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select I Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C oc Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar Measurement trigger selection prior stage and the last stage. tocol Triggering Option WM8Zi-6GBIT-80b-SYM	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s ren state (or transition edge) has constant to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select early specifying the expected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I asurement): Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic), and C, C and D is selectable by time in as the last stage in a Cascade put MBOL-TD: 600 Mb/s to 6.5 Gb/s, Cl	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between the description of the condition of	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff High-speed Serial Prof	Triggers on positive or negative. Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a give. Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select 1 Trigger on edge rates. Select 1 Trigger on intermittent faults between of the money of th	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s ren state (or transition edge) has constant to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select early specifying the expected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Triggiow, Pattern (Logic) Width, Glitch, I asurement): Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic), and C, C and D is selectable by time in as the last stage in a Cascade put MBOL-TD: 600 Mb/s to 6.5 Gb/s, Cl'MBOL-TD: 600 Mb/s to 14.1 Gb/s	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between the description of the d	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea- an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff High-speed Serial Prof	Triggers on positive or negative. Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a give. Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select 1 Trigger on edge rates. Select 1 Trigger on intermittent faults between of the money of th	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s ren state (or transition edge) has constant to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select early specifying the expected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I asurement): Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic), and C, C and D is selectable by time in as the last stage in a Cascade put MBOL-TD: 600 Mb/s to 6.5 Gb/s, Cl	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between the description of the d	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea- an be on Stage D only.

Pattern Length	80 bits NRZ, eight 8b/10b symbols, 64b/66b symbol
Clock and Data Outputs	No Clock and Data Recovery outputs provided

Low Speed Serial Protocol Triggering (Optional)

I²C, SPI (SPI, SSPI, SIOP), UART-RS232, CAN, LIN, FlexRay, MIL-STD-1553, AudioBus

Measurement Trigger

SMART Trigger External Trigger External Trigger External Trigger Edge Basic Triggers Edge Window Triggers wh Triggers wh Triggers wh Triggers wh (50 or 60 Hz (1:1, 2:1, 4:1) SMART Triggers™ State or Edge Qualified Triggers on lectable by Qualified First In Sequence is satisfied Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Interval (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on (State/Edge Qualified) Runt Trigger on interval (Signal or Pattern) Slew Rate Exclusion Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A Stage B on Cascade A Stage B on Cascade A Surement of Cascade A Cascade A Holdoff Holdoff bet Measurement	500 MHz 200 MHz 2upling) ≥ 10 mV/div (minin /); Aux/10 (±4 V) men signal meets slopen signal exits a w FSC or PAL with selopen and Line or CUSTO 1, 8:1), or Synch Pul many input source of time or events are acquisition mode in the first segment signal drops out for bination (AND, NANE	ope (positive, negative, or either) are rindow defined by adjustable thresh ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occur	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
1.0 div @ <	200 MHz upling) ≥ 10 mV/div (minin r); Aux/10 (±4 V) men signal meets slanen signal exits a w FSC or PAL with sela z) and Line or CUSTO 1, 8:1), or Synch Pul an any input source of time or events be acquisition mode in the first segment signal drops out for bination (AND, NANE	ope (positive, negative, or either) and indow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occurs, triggers repeatably on event B on at of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
Max. Trigger Frequency, SMART Trigger External Trigger Aux (±0.4 V Input Range) Basic Triggers Edge Triggers Window Window Triggers Window Window Triggers Window Win	upling) ≥ 10 mV/div (minin /); Aux/10 (±4 V) nen signal meets slenen signal exits a w FSC or PAL with select 2) and Line or CUST(1, 8:1), or Synch Pul n any input source of time or events are acquisition mode in the first segment signal drops out for bination (AND, NANE)	ope (positive, negative, or either) and indow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occurs, triggers repeatably on event B on at of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
Max. Trigger Frequency, SMART Trigger External Trigger Input Range Basic Triggers Edge Triggers with Triggers with Triggers with SMART Triggers State or Edge Qualified In Sequence is satisfied Dropout Triggers if sequence is satisfied Dropout Triggers if sequence is satisfied Dropout Triggers on Care. The H SMART Triggers with Exclusion Triggers on Interval (Signal or Pattern) Interval (Signal or Pattern) Triggers on Interval (Signal or Pattern) Slew Rate Trigger on Exclusion Triggering Cascade (Sequence) Triggering Trigger on Cascade A Stage B on Cascade A Stage B on Cascade A Holdoff bet Measurement or Stage Prior stage	≥ 10 mV/div (minin /); Aux/10 (±4 V) nen signal meets slenen signal exits a w FSC or PAL with select) and Line or CUST(1, 8:1), or Synch Pul n any input source of time or events the acquisition mode in the first segment signal drops out for bination (AND, NANE)	ope (positive, negative, or either) and indow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occurs, triggers repeatably on event B on at of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
SMART Trigger External Trigger External Trigger Input Range Basic Triggers Edge Triggers where Window Window Triggers on Lectable by In Sequence is satisfied Dropout Triggers if some Vindow Window Windo	nen signal meets slanen signal exits a writer sland control of the signal exits a writer sland control of the sland control of the sland control of the sland control of the first segments signal drops out for bination (AND, NANE)	ope (positive, negative, or either) and indow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occurs, triggers repeatably on event B on at of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
Basic Triggers Edge Triggers when down down down down down down down dow	nen signal meets slo nen signal exits a w FSC or PAL with selo z) and Line or CUST(1, 8:1), or Synch Pul n any input source of time or events re acquisition mode in the first segment signal drops out for bination (AND, NANE	rindow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occur, triggers repeatably on event B on it of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
Edge Triggers where Window Triggers with TV-Composite Video Triggers NT (50 or 60 Hz (1:1, 2:1, 4:1) SMART Triggers™ State or Edge Qualified Triggers on lectable by Qualified First In Sequence is satisfied Dropout Triggers if sequence is satisfied Triggers if sequence is satisfied Triggers if sequence is satisfied Triggers on Care. The Help Triggers on Interval (Signal or Pattern) Trigger on I	nen signal exits a w FSC or PAL with sele z) and Line or CUST(1, 8:1), or Synch Pul an any input source of time or events are acquisition mode in the first segment signal drops out for bination (AND, NANE	rindow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occur, triggers repeatably on event B on it of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
Window Triggers who should be a surement of Cascade A surement of Cascade A Holdoff bet Measuremen and to 1:1, 2:1, 4:1 Window Triggers with Triggers on lectable by (1:1, 2:1, 4:1) SMART Triggers State or Edge Qualified Triggers on lectable by In Sequence is satisfied Triggers if should be part of the care. The Holdoff bet Triggers on Interval (Signal or Pattern) Cascade (Sequence) Trigger on Interval (Signal or Patte	nen signal exits a w FSC or PAL with sele z) and Line or CUST(1, 8:1), or Synch Pul an any input source of time or events are acquisition mode in the first segment signal drops out for bination (AND, NANE	rindow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occur, triggers repeatably on event B on it of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
TV-Composite Video Triggers NT (50 or 60 Hz (1:1, 2:1, 4:1) SMART Triggers State or Edge Qualified Qualified First In Sequence is satisfied Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on State/Edge Qualified) Runt Trigger on p Slew Rate Exclusion Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A Stage B on Cascade A Surement C Cascade A Holdoff bet Measureme prior stage	rSC or PAL with select) and Line or CUST(1, 8:1), or Synch Pular any input source of time or events are acquisition mode in the first segment signal drops out for bination (AND, NANE)	ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lse Slope (Positive or Negative) only if a defined state or edge occure, triggers repeatably on event B on tof the acquisition. Holdoff between longer than selected time between	1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 cred on another input source. Hol by if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
SMART Triggers State or Edge Qualified Qualified First Dropout Pattern SMART Triggers with Exclusion Triggers on Lacre. The H SMART Triggers with Exclusion Triggers on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A Stage B on Cascade A Surement C Cascade A Cascade A Holdoff bet Measuremen prior stage	z) and Line or CUST(1, 8:1), or Synch Pul n any input source of time or events re acquisition mode in the first segment signal drops out for bination (AND, NANE	OM with selectable Fields (1–8), Line lse Slope (Positive or Negative) only if a defined state or edge occur e, triggers repeatably on event B on tof the acquisition. Holdoff between longer than selected time between	es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing
State or Edge Qualified Qualified First Qualified First In Sequence is satisfied Dropout Pattern Care. The H SMART Triggers with Exclusion Telegres on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on Holdoff bet Runt Slew Rate Exclusion Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A Stage B on Cascade A Surement of Cascade A Cascade A Cascade A Holdoff bet Measuremen prior stage	time or events the acquisition mode in the first segment signal drops out for bination (AND, NAND	e, triggers repeatably on event B on tof the acquisition. Holdoff betwee longer than selected time between	ly if a defined pattern, state, or ec	Idoff between sources is se-
Qualified First In Sequence is satisfied Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Interval (Signal or Pattern) Triggers on Interval (State/Edge Qualified) Holdoff bet Exclusion Triggering Trigger on interval (Sequence) Trigger on interval (Sequence) Triggering Trigger on interval (Sequence) Triggering Trigger on interval (Sequence) Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A Stage B on Interval (Sequence) Triggering Cascade A	time or events the acquisition mode in the first segment signal drops out for bination (AND, NAND	e, triggers repeatably on event B on tof the acquisition. Holdoff betwee longer than selected time between	ly if a defined pattern, state, or ec	ldoff between sources is se-
is satisfied Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on (State/Edge Qualified) Holdoff bet Runt Trigger on p Slew Rate Trigger on or Exclusion Triggering Cascade (Sequence) Triggering Types Cascade A Stage B on Cascade A Stage B on Cascade A Stage B on Cascade A Surement or Cascade A Holdoff Holdoff bet Measuremen prior stage	in the first segment signal drops out for bination (AND, NAND	t of the acquisition. Holdoff between longer than selected time between		
Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Interval (Signal or Pattern) Triggers on Interval (Sign	signal drops out for pination (AND, NANE	longer than selected time between	en sources is selectable by time of	
Pattern Logic combotance Care. The H SMART Triggers with Exclusion T Glitch Triggers on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on (State/Edge Qualified) Holdoff bet Runt Trigger on p Slew Rate Trigger on or Exclusion Triggering Trigger on or Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A Stage B on Cascade A Stage B on Cascade A Surement or Cascade A Holdoff Holdoff bet Measuremen prior stage	pination (AND, NANE			2. 2.0
SMART Triggers with Exclusion T Glitch Triggers on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on (State/Edge Qualified) Holdoff bet Runt Trigger on p Slew Rate Trigger on or Exclusion Triggering Trigger on or Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A Surement or Cascade A Holdoff Holdoff bet Measuremen prior stage		2, 3, 11011, 01 0 mpato (+ onal litelo		source can be high low or don
Glitch Triggers on Width (Signal or Pattern) Triggers on Interval (State/Edge Qualified) Holdoff bet Runt Trigger on Exclusion Triggering Trigger on Exclusion Triggering Trigger on Interval (Sequence) Triggering Trigger on Interval (Sequence) Triggering Cascade (Sequence) Triggering Arm on "A" event, then Types Cascade A Stage B on Cascade A surement of Cascade A Cascade A Holdoff Holdoff bet Measurement of Cascade A Holdoff bet Measurement of Stage Bon Cascade A Holdoff bet Measurement of Cascade A Holdoff bet	igh and Low level ca	an be selected independently. Trigge		Journe dan be riigh, lovy, or don
Width (Signal or Pattern) Interval (Signal or Pattern) Triggers on Triggers on Triggers on Triggers on Triggers on Holdoff bet Runt Trigger on Slew Rate Trigger on Exclusion Triggering Trigger on Exclusion Triggering Trigger on Tri		19.1 20.122		20 C . II
Interval (Signal or Pattern) Triggers on Timeout Triggers on Runt Trigger on p Slew Rate Trigger on or Exclusion Triggering Trigger on or Exclusion Triggering Trigger on or Trigger on		e glitches with widths selectable as		
Timeout (State/Edge Qualified) Holdoff bet Runt Trigger on public Slew Rate Trigger on its Exclusion Triggering Exclusion Trigger on its Exclusion Trig	positive, negative, or	r both widths with widths selectable a	as low as 200 ps to 20 s, or on inte	rmittent faults
(State/Edge Qualified) Runt Trigger on p Slew Rate Trigger on p Exclusion Triggering Trigger on p Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A surement of Cascade A Holdoff Holdoff Holdoff bet Measuremen prior stage		e between 1 ns and 20 s		
Runt Trigger on p Slew Rate Trigger on p Exclusion Triggering Trigger on i Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A surement of Cascade A Holdoff Holdoff Holdoff bet Measureme prior stage		ren state (or transition edge) has oc		
Slew Rate Trigger on a Exclusion Triggering Trigger on a Trigger on a Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A surement of Cascade A Cascade A Holdoff Holdoff Holdoff bet Measurement prior stage		ns to 20 s, or 1 to 99,999,999 event		1 100
Exclusion Triggering Trigger on it Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B onl Cascade A surement of Cascade A Cascade A Holdoff Holdoff bet Measurement of Measurement of Measurement of Cascade A Cascade A Total Measurement Prior stage		runts defined by two voltage limits a		
Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A surement of Cascade A Cascade A Holdoff Holdoff Holdoff bet Measureme prior stage		imits for dV, dt, and slope. Select ed		
Capability Arm on "A" event, then Types Cascade A Stage B onl Cascade A surement of Cascade A Cascade A Holdoff Holdoff Holdoff bet Measureme prior stage	mermittent rauns t	by specifying the expected behavio	r and triggering when that condi-	tion is not met
event, then Types Cascade A Stage B onl Cascade A surement o Cascade A Cascade A Holdoff Holdoff Holdoff bet Measureme prior stage	event then Trigger	on "B" event. Or Arm on "A" event, t	hen Qualify on "B" event, and Tric	gger on "C" event Or Arm on "i
Types Cascade A Stage B onl Cascade A surement of Cascade A Cascade A Holdoff Holdoff Holdoff bet Measurement prior stage		"C" event, and Trigger on "D" event		iger on C event. Or Annon A
Stage B onl Cascade A surement of Cascade A Cascade A Holdoff Holdoff Holdoff Measurement prior stage	thon P: Edgo Wind	ow, Pattern (Logic) Width, Glitch, In	storyal Drangut or Maggurament	t Massurament can be on
Cascade A surement of Cascade A Cascade A Holdoff Holdoff Measurement prior stage		ow, rattern (Logic) Width, Gilton, in	iterval, bropout, or incasurement	Wedsdreffield dail be off
surement of Cascade A Cascade A Holdoff Holdoff Measurement of the prior stage	,	asurement): Edge, Window, Pattern	(Logic) Width Glitch Interval Dr	ropout or Measurement Mea
Cascade A Cascade A Holdoff Holdoff Measureme prior stage	can be on Stage C o		(Logio), Width, Onton, Interval, Dr	opeat, or incadarement. mea
Cascade A Holdoff Holdoff Measureme prior stage		e, Window, Pattern (Logic).		
Holdoff Holdoff bet Measureme prior stage	9	D: Edge, Window, Pattern (Logic), o	or Measurement, Measurement o	can be on Stage D only
Measureme prior stage	ween A and B B ar	nd C, C and D is selectable by time (Ins to 20s) or number of events	i
prior stage		n as the last stage in a Cascade pre		
· -	and the last stage.			
High-speed Serial Protocol Trigge				
	ering			
Data Rates	Option WM8Zi-6G	BIT-80b-SYMBOL-TD: /s, Channel 4 input only	Option WM8Zi-6GBl 600 Mb/s to 6.5 Gb/s,	
		GBIT-80b-SYMBOL-TD:	Option WM8Zi-14GBI	· · · · · · · · · · · · · · · · · · ·
6	· ·	o/s, Channel 4 input only	600 Mb/s to 14.1 Gb/s	
(Note:	Channel 3 input will	Il capture signal for triggering e is in ≥25 GHz mode)	(Note: Channel 3 input will c when oscilloscope is	
		on SDA models:	(Standard on S	SDA models:
	when oscilloscope (Standard o		600 Mb/s to 6.5 Gb/s,	
60	when oscilloscope (Standard o 600 Mb/s to 6.5 Gb/	ACDIT OOK OVAROU TO	Option SDA8Zi-UPG-140 600 Mb/s to 14.1 Gb/s,	
Pattern Length 80 bits NR2	when oscilloscope (Standard o 500 Mb/s to 6.5 Gb/ otion SDA8Zi-UPG-1 00 Mb/s to 14.1 Gb/	/s, Channel 4 input only)		

Low Speed Serial Protocol Triggering (Optional)

I²C, SPI (SPI, SSPI, SIOP), UART-RS232, CAN, LIN, FlexRay, MIL-STD-1553, AudioBus

Measurement Trigger

Color Waveform Display	WaveMaster 804Zi-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
Гуре	Color 15.3" flat panel TFT-Activ	ve Matrix LCD with high resolution	n touch screen	
Resolution	WXGA; 1280 x 768 pixels			
Number of Traces	Display a maximum of 16 trac math traces.	es (up to 40 with some software	options). Simultaneously display c	hannel, zoom, memory and
Grid Styles	Auto, Single, Dual, Triple, Quad Up to twenty grids available w	, Octal, X-Y, Single+X-Y, Dual+X-Y, ith some software options	Twelve, Sixteen.	
Waveform Representation	Sample dots joined, or sample			
ntegrated Second Dis	enlav			
ntegrated occord bis	<u> </u>	tion of user-supplied second dis	play with split-grid capability.	
		second display may not be a Fuji		
Processor/CPU				
Гуре	Intel® CoreTM i7-4770S Quad	, 3.1 GHz (up to 3.9 GHz in Turbo	mode) (or better)	
Processor Memory		y (32 Mpt), and M-64 memory or		
Operating System	Microsoft Windows® 7 Profess	sional Edition (64-bit)		
Real Time Clock			NTP support to synchronize to pred	cision internal clocks
nterface				
Remote Control	Via Windows Automation, or v	ia Teledyne LeCroy Remote Com	mand Set	
Network Communication Standard	VXI-11 or VICP, LXI Class C (v1			
GPIB Port (Optional)	Supports IEEE - 488.2			
SIB Port (Optional)	Supports PCIe Gen1 x4 protoc	ol with Teledyne LeCroy supplied	API	
Ethernet Port	Supports 10/100/1000BaseT			
JSB Ports		2.0 ports (front panel) support W		
External Monitor Port	Full-size DisplayPort connecto	r to support customer-supplied of	external monitor.	
	Includes support for extended	desktop operation with second i	monitor.	
Serial Port	Not Available			
Power Requirements Voltage	100-240 VAC ±10% at 45-66	Hz, 100-120 VAC ±10% at 380-	-420 Hz, Automatic AC Voltage Sele	ection, Installation Categor
Max. Power Consumption	975 W / 975 VA		<u> </u>	<u> </u>
Environmental				
Temperature (Operating)	+5 °C to +40 °C			
Temperature	-20 °C to +60 °C			
(Non-Operating)	20 0 10 100 0			
Humidity	5% to 80% relative humidity (n	on-condensing) up to +31 °C.		
Operating)		ative humidity (non-condensing)	at +40 °C	
Humidity		on-condensing) as tested per MI		
Non-Operating)	, ,	3/		
Altitude	Up to 10,000 ft. (3048 m) at or	below +25 °C		
Operating) Random Vibration	0.5 a _{rms} 5 Hz to 500 Hz 15 mi	nutes in each of three orthogona	laxes	
Operating)				
Random Vibration (Non-Operating)	2.4 g _{rms} 5 Hz to 500 Hz, 15 mi	nutes in each of three orthogona	l axes	
Functional Shock	20 g _{peak} , half sine, 11 ms pulse,	3 shocks (positive and negative)	in each of three orthogonal axes, 18	shocks total
Physical Dimensions				
Dimensions (HWD)		467 x 406 mm) height excludes f	eet	
Weight	51.5 lbs. (23.4 kg)	, J		
Shipping Weight	70 lbs. (31.8 kg)			
Certifications				
J. HIIVANOIIO	CE Compliant, UL and cUL listed CSA C22.2 No. 61010-1-12	d; conforms to EN 61326, EN 6101	0-1, EN61010-2-030, UL 61010-1 3rd	d edition, and
Warranty and Service				
with out the	3-year warranty calibration rec	commended annually.		
		lude extended warranty, upgrade	s, and calibration services	
	. •	, . ,		

Fige Color 18.3° flat pond FTF-Active Natrix (CO with high resolution butch screen WXX64, 1926 768 push Number of Traces Display or reakman of 16 traces (up to 49 with some software options). Simultaneously display channel, zoom, memory and month traces. Grid Styles Auto. Single, Dual, Taple, Quad, Ortal, X-Y, Singler-K-Y, Dual-X-Y, Twelve, Suteen Use to twenty ords evalible with some software options. Waveform Representation Sample dolds jorted, or sample dolds only Number of Display Integrated Second Display Supports studin screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with screen integration of users scr	Color Waveform Display	WaveMaster 816Zi-B (SDA)	WaveMaster 820Zi-B (SDA, DDA)	WaveMaster 825Zi-B (SDA)	WaveMaster 830Zi-B (SDA)
Number of Traces Display a maximum of 16 traces up to 40 with some software options. Brid Styles Auto, Single, Dual, Triple, Quad, Octal, X*Y Single-XY, Dual-XY, Twelve, Sindeen. Up to twenty gine available with some software options. Western Representation Sample dots joined, or sample dots only Integrated Second Display Supports touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. Processor/CPU Type. Processor/CPU Type. Interded Screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration (St Mit) to 3 9 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0		Color 15.3" flat panel TFT-Acti			•
math traces. Auto, Single, Dual, Triple, Quad, Octal, XY, Single-XY, Dual+XY, Twelve, Sixteen. Dual traces and the second octal oct	Resolution				
Weekform Representation Sample date joined, or sample date with some software options. Weekform Representation Sample date joined, or sample date on the sample date of the sample date	Number of Traces		ees (up to 40 with some software op	otions). Simultaneously display	channel, zoom, memory and
Augusted Second Display Supports touch screen integration of user-supplied second display with spit-grid capability. (Note: touch screen driver for second display may not be a Fujitau driver) Processor/CPU Viscosor/CPU Viscos	Grid Styles		•	welve, Sixteen.	
Supports touch screen integration of user-supplied second display with spit-grid capability. (Note touch screen driver for second display may not be a Fujitsu driver) Processor/CPU Type Intel® CoreTM 17-4770S Quad. 3.1 GHz (up to 3.9 GHz in Turbo mode) (or better) Tocessor Memory 8 6 B standard for 1770 memory (32 Mgy), and Mc42 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard with the spit of t	Waveform Representation				
Supports touch screen integration of user-supplied second display with split-grid capability. [Note: touch screen driver for second display may not be a Fujitsu driver) Processor/CPU Type Intel® CoreTM (7-4770S Quad. 3.1 GHz (up to 3.9 GHz in Turbo mode) (or better) Forecessor Memory 8 6 B standard for 1770 memory (32 Mpt), and M-64 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard v2-128 memory options 17 GB standard v2-128 memory options 18 memory options	Integrated Second Dis	nlav			
Processor/CPU Type Intel® CoreTM I7 4770S Quad, 8.1 GHz (up to 2.9 GHz in Turbo mode) (or better) 8 GB standard for STD memory (32 Mpt), and M-64 memory options 16 GB standard for L128 and VL 256 memory options 16 GB standard for L128 and VL 256 memory options 16 GB standard for L128 and VL 256 memory options 19 to 32 GB optional Determine Control Via Windows Automation, or via Teledyne LeCroy Remote Command Set Verwork Communication VX+11 or ViCP, LX Class G (v.1.2) Compliant Standard Supports IEEE – 488.2 SIB Pott (Optional) Supports Individe SIB Pott Sib Potter (Optional) Supports IEEE – 488.2 SIB Pott (Optiona	integrated Second Dis	Supports touch screen integra			
Processor Memory B GB standard for 1719 and VI-26 memory options 16 GB standard for 1719 and VI-26 memory options 16 GB standard for 1719 and VI-26 memory options 16 GB standard for 1719 and VI-26 memory options 17 GB standard for 1719 and VI-26 memory options 18 GB standard for 1719 and VI-26 memory options 19 GB optional 20 perating System Microsoft Windows* 7 Professional Edition (64-bit) 19 Determined System Microsoft Windows* 7 Professional Edition (64-bit) 10 Determined System Microsoft Windows* 7 Professional Edition (64-bit) 10 Determined System Microsoft Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication VI-11 or VICPLXI Class C (VI.2) Compliant 18 Determined Standard 18 Determined Supports IEEE – 488.2 18 BPOT (Optional) 18 Determined Supports IEEE – 488.2 18 BPOT (Optional) 18 Supports IEEE – 488.2 18 BPOT (Optional) 19 Supports IEEE – 488.2 19 Supports IEEE –	Processor/CPU	(,	
16 GB standard for L-128 and VL-256 memory options	Туре	Intel® CoreTM i7-4770S Quad	l, 3.1 GHz (up to 3.9 GHz in Turbo m	node) (or better)	
Deersting System Microsoft Windows* 7 Professional Edition (64 bit) Remail Time Clock Date and time displayed with waveform an in hardcopy files. SNTP support to synchronize to precision internal clocks Interface Network Communication Via Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication VXI-11 or VICP, LXI Class C (V1.2) Compliant Standard Standard Standard Supports EEE 488.2 Supports EEE 488.2 Supports EEE 488.2 Supports Port (Optional) Supports PCIG earl V4 protocol with Teledyne LeCroy supplied API Subports Port Supports PCIG earl V4 protocol with Teledyne LeCroy supplied API Subports Pull-size Displayer of connector to support clustomer supplied external monitor Includes support for extended desktop operation with second monitor. Serial Port Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100-240 VAC ±10% at 45-66 Hz, 100-120 VAC ±10% at 380-420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 VA Privionmental Peripheral U2 Power Priving Peripheral U3 Power Priving Priving Power Priving P	Processor Memory	16 GB standard for L-128 and		ons	
### Page 12 Page 13 Page 14 Pa	Operating System		sional Edition (64-bit)		
Remote Control Via Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication VXH-11 or VICP, LXI Class C (V.12) Compliant Standard SPIB Port (Optional) Supports IEEE – 488.2 SIB Port (Optional) Supports DCIe Gen1 x4 protocol with Teledyne LeCroy supplied API Sibrory Automatic Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SI		Date and time displayed with w	aveform an in hardcopy files. SNTP s	support to synchronize to precision	on internal clocks
Remote Control Via Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication Standard SepiB Port (Optional) Supports IEEE – 488.2 SIB Port (Optional) Supports DCic Gen1 x4 protocol with Teledyne LeCroy supplied API Stehenet Port Supports 107.1007.10008ase1 Ethernet interface (R.J45 port) Supports 107.10008ase1 Ethernet interface (R.J45 port) Supports 107.10008ase1 Ethernet interface (R.J45 port) Supports 107.10008ase1 Ethe	nterface				
Network Communication VXI-11 or VICP, LXI Class C (v1.2) Compliant Standard SPIB Port (Optional) Supports IFEE = 488.2 Susib Port (Optional) Supports IFEE = 488.2 Susib Port (Optional) Supports IFEE = 488.2 Susib Port (Optional) Supports IFEE = 488.2 Susports Ports Supports If VICP/ LOUGBaser Ethernet interface (RJ45 port) USB Ports 4 USB 3.0 ports (rean), 3 USB 2.0 ports (front panel) support Windows compatible devices External Monitor Port Includes support for extended desktop operation with second monitor. Includes support for extended desktop operation with second monitor. Includes Support for extended desktop operation with second monitor. Serial Port Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100-240 VAC ±10% at 45-66 Hz. 100-120 VAC ±10% at 380-420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption Environmental Temperature 45 °C to +40 °C (Operating) Humidity 5% to 80% relative humidity (non-condensing) up to +31 °C. (Operating) Humidity 5% to 80% relative humidity (non-condensing) as tested per MIL-PRF-28800F (Non-Operating) Altitude (Operating) Altitude (Operati		Via Windows Automation, or v	ria Teledyne LeCroy Remote Comma	and Set	
Supports PCIe Gent xd protocol with Teledyne LeCroy supplied API	Network Communication				
Ethernet Port Supports 10/100/100/BaseT Ethernet interface (R.J.45 port) JSB Ports 4 USB 3.0 ports (rear), 3 USB 2.0 ports (front panel) support Windows compatible devices External Monitor Port Includes support to extended desktop operation with second monitor. Includes support for extended desktop operation with second monitor. Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W					
JUSB 20 ports (rear), 3 USB 2.0 ports (front panel) support Windows compatible devices Seternal Monitor Port Full-size DisplayPort connector to support customer-supplied external monitor. Includes support for extended desktop operation with second monitor. Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W A 1025 W / 1025 W A Environmental Femperature +5 °C to +40 °C Operating) - 20 °C to +60 °C Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) up to +31 °C. Upperating) - Upper limit derates to 50% relative humidity (non-condensing) at +40 °C - Humidity 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per				PI	
External Monitor Port Includes support for extended desktop operation with second monitor. Includes support for extended desktop operation with second monitor. Serial Port Not Available Teledyne LeCroy LBUS standard Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 VA Included 1025 W / 1025 W / 1025 VA Included 1025 W / 1025 W / 1025 VA Included 1025 W / 1025 W / 1025 W / 1025 W /					
Includes support for extended desktop operation with second monitor. Serial Port Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100-240 VAC ±10% at 45-66 Hz, 100-120 VAC ±10% at 380-420 Hz, Automatic AC Voltage Selection, Installation Category Max Power Consumption 975 W / 975 VA 1025 W / 1025 VA Invironmental Temperature 45 °C to +40 °C Operating) Humidity 5% to 80% relative humidity (non-condensing) up to +31 °C. Upper limit derates to 50% relative humidity (non-condensing) at +40 °C Upperating) Humidity 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) Non-Operating) Non-Operating) Non-Operating) Altitude Up to 10,000 ft. (3048 m) at or below +25 °C Operating) Random Vibration Operating) Non-Operating) Non-Operating) Power Requirements 2.4 g _{ms} 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes Operating) Non-Operating) Non-Operating) Power Requirements 14* H x 18.4* W x 16* D (355 x 467 x 406 mm) height excludes feet Neight 10* Standard Vibration Non-Operating) 14* H x 18.4* W x 16* D (355 x 467 x 406 mm) height excludes feet Neight 10* Standard Vibration Non-Operating) CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12					
Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100-240 VAC ±10% at 45-66 Hz, 100-120 VAC ±10% at 380-420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W / 1025 VA Invironmental Invir		Includes support for extended			
Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W / 1025 W / Environmental Temperature					
Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W A 1025 W / 1025 W A 102	Peripheral Bus	releayne LeCroy LBUS standa	ira		
Servironmental		100 040 //40 /100/ / 45 66	11. 100. 100 \\0.00. 100\\0.00\0.00\0.00\\0.00\0.00\\0.00\	2011 4 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	
Environmental Temperature					
Temperature	Max. Power Consumption	975 W	/ / 975 VA	1025 W /	′ 1025 VA
Coperating Cop		+5 °C to +10 °C			
Non-Operating) Humidity Goperating Upper limit derates to 50% relative humidity (non-condensing) at +40 °C Humidity S% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) Altitude Up to 10,000 ft. (3048 m) at or below +25 °C Operating) Random Vibration Operating) Random Vibration Operating) Random Vibration Unough S Hz to 500 Hz, 15 minutes in each of three orthogonal axes Operating) Random Vibration Operating) Random Vibration Operating) Random Vibration Operating) Random Vibration Operating) Physical Dimension Dimensions Universions Universio	•	+5 0 10 +40 0			
Operating) Upper limit derates to 50% relative humidity (non-condensing) at +40 °C Humidity 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) Altitude Up to 10,000 ft. (3048 m) at or below +25 °C Operating) Random Vibration Operating) Random Vibration Operating) Random Vibration Operating) Punctional Shock 2.4 grms 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes Non-Operating) Functional Shock 20 g _{peak} , half sine, 11 ms pulse, 3 shocks (positive and negative) in each of three orthogonal axes, 18 shocks total Physical Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight 70 lbs. (31.8 kg) CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		−20 °C to +60 °C			
Humidity (Non-Operating) Altitude (Operating) Random Vibration (Non-Operating) Functional Shock 20 g _{peak} , half sine, 11 ms pulse, 3 shocks (positive and negative) in each of three orthogonal axes, 18 shocks total Physical Dimension Dimensions (HWD) 14* H x 18.4* W x 16* D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12	Humidity				
(Non-Operating) Altitude	(Operating)				
Altitude (Operating) Random Vibration (Operating) Random Vibration (Operating) Random Vibration (Operating) Random Vibration (Non-Operating) Functional Shock 20 g _{peak} , half sine, 11 ms pulse, 3 shocks (positive and negative) in each of three orthogonal axes, 18 shocks total Physical Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) CEt Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12	Humidity	5% to 95% relative humidity (n	on-condensing) as tested per MIL-F	PRF-28800F	
Operating) Random Vibration Non-Operating) Functional Shock Operating) Physical Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) Shipping Weight Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12					
Anandom Vibration Operating) Random Vibration Operating) 2.4 g _{rms} 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes Non-Operating) Functional Shock Operating Operating The specific of the specific of three orthogonal axes Operating Operating		Up to 10,000 ft. (3048 m) at o	r below +25 °C		
Random Vibration (Non-Operating) Functional Shock 2.4 g _{rms} 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes (Non-Operating) Functional Shock 20 g _{peak} , half sine, 11 ms pulse, 3 shocks (positive and negative) in each of three orthogonal axes, 18 shocks total Physical Dimension Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		0.5 g _{rms} 5 Hz to 500 Hz, 15 m	inutes in each of three orthogonal a	xes	
Physical Dimension Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight Shipping Weight CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		2.4 g _{rms} 5 Hz to 500 Hz, 15 mi	nutes in each of three orthogonal a	xes	
Physical Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		00 1. 15 1. 22	O alterative for a 191 and 191	and the state of t	0 -111
Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12	Functional Shock	20 g _{peak} , half sine, 11 ms pulse	, 3 shocks (positive and negative) in (each of three orthogonal axes, 1	8 shocks total
Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		14"11 v 10 4" \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	467 v 406 pops) hainhall. 5		
Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12					(26.41m)
CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12			, ,,		
CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12	Snipping Weight	/0 lbs	. (उ1.8 Kg)	/6.0 lbs.	(34.5 Kg)
CSA C22.2 No. 61010-1-12	Certifications				
Narranty and Service			d; conforms to EN 61326, EN 61010-	1, EN61010-2-030, UL 61010-1 3	rd edition, and
	Warranty and Service				

Standard

Math Tools

Display up to 8 math function traces (F1 - F8). The easy-to-use graphical interface simplifies setup of up to two operations on each function trace, and function traces can be chained together to perform math-on-math.

absolute value integral

average (summed) interpolate (cubic, quadratic, sinx/x)

average (continuous) invert (negate)
correlation log (base e)
(two waveforms) log (base 10)
derivative product (x)
deskew (resample) ratio (/)
difference (-) reciprocal

enhanced resolution (to 11-bits vertical) rescale (with units)

envelope exp (base e) square exp (base 10) square root square root square root sum (+) grown floor square root som (identity)

Measure Tools

Display any 12 parameters together with statistics, including their average, high, low, and standard deviations. Histicons provide a fast, dynamic view of parameters and wave shape characteristics. Parameter Math allows addition, subtraction, multiplication, or division of two different parameters.

amplitude level @ x rms
area maximum std. deviation
base mean top
cycles median width
data minimum phase

time @ minimum (min.) delay narrow band phase Δ delay narrow band power time @ maximum (max.) number of points Δ time @ level duty cycle duration + overshoot Δ time @ level from trigger falltime (90-10%, - overshoot 80-20%, @ level) x @ max. peak-to-peak frequency x @ min. period

first risetime (10–90%, last 20–80%, @ level)

Pass/Fail Testing

Simultaneously test multiple parameters against selectable parameter limits or pre-defined masks. Pass or fail conditions can initiate actions including document to local or networked files, e-mail the image of the failure, save waveforms, send a pulse out at the front panel auxiliary BNC output, or (with the GPIB option) send a GPIB SRQ.

Basic Jitter and Timing Analysis Tools

This package provides toolsets for displaying parameter values vs. time, statistical views of parameters using histograms, and persistence view math functions. These tools include:

· "Track" graphs of all parameters, no limitation of number

Cycle-Cycle Jitter
 N-Cycle
 N-Cycle with
 N-Cycle with
 Start selection

- Period @ level

 Hold
 Skew

- Time Interval
- Duty 6

- Time Interval - Duty Cycle @ level - Duty Cycle @ level - Duty Cycle Error

- · Histograms expanded with 19 histogram parameters and up to 2 billion events
- Trend (datalog) of up to 1 million events
- Track graphs of all parameters
- Persistence histogram, persistence (range, sigma)

Standard (cont'd)

Advanced Customization

Provides capability to create a math function or measurement parameter in MATLAB, Excel, C++, JavaScript, or Visual Basic Script (VBS) format and insert it into the oscilloscope's processing stream. All results are processed and displayed on the oscilloscope grid, and are available for further processing. Also permits the creation of customized plug-ins that can be inserted into the scope user interface, control of the scope via Visual Basic scripts embedded in customized functions, and use of Teledyne LeCroy's Custom DSO capabilities.

Software Options

SDAIII Serial Data Analysis Software (WM8Zi-SDAIII) (Included in WM8Zi-SDAIII option, Standard on SDA 8 Zi-B and DDA 8 Zi-B Models)

Total Jitter

A complete jitter measurement and analysis toolset with the SDAIII-CompleteLinQ user interface framework. The CompleteLinQ framework provides a single user interface for "LinQ", "Crosstalk", "EyeDrII" and "Virtual Probe" capabilities (purchased separately).

SDAIII provides complete serial data and clock jitter and eye diagram measurement and analysis capabilities. Eye Diagrams with millions of UI are quickly calculated from up to 512 Mpt records, and advanced tools may be used on the Eye Diagram to aid analysis. Complete TIE and Total Jitter (Tj) parameters and analysis functions are provided. Comparison of eye diagrams and jitter analysis between captured lanes and one "reference" location is provided. Includes:

- Time Interval Error (TIE) Measurement Parameter, Histogram, Spectrum and Jitter Track
- Total Jitter (Tj) Measurement Parameter, Histogram
- Spectrum
- Eye Diagram Display (sliced)
- Eye Diagram IsoBER (lines of constant Bit Error Rate)
- Eye Diagram Mask Violation Locator
- · Eye Diagram Measurement Parameters

Eye Height
One Level
Zero Level
Eye Crossing
Mask out
Mask out
Bit Error Rate
Eye Amplitude
Extinction Ratio
Slice Width (setting)

- Q-Fit Tail Representation
- Bathtub Curve
- Cumulative Distribution Function (CDF)
- PLL Track

Jitter Decomposition Models

Three dual-dirac jitter decomposition methods are provided for maximum measurement flexibility. Q-Scale, CDF, Bathtub Curve, and all jitter decomposition measurement parameters can be displayed using any of the three methods.

- · Spectral, Rj Direct
- Spectral, Rj+Dj CDF Fit
- · NQ-Scale

Random Jitter (Rj) and Non-Data Dependent Jitter (Rj+BUj) Analysis

Random Jitter (Rj) Meas Param
 Periodic Jitter (Pj) Meas Param
 Rj+BUj Spectrum
 Rj+BUj Track
 Rj+BUj Histogram
 Pj Inverse FFT

Deterministic Jitter (Dj) Analysis

· Deterministic Jitter (Dj) Measurement Parameter

Software Options (cont'd)

SDAIII Serial Data Analysis Software (continued)

Data Dependent Jitter (DDj) Analysis

- · Data Dependent Jitter (DDj) Param
- Duty Cycle Distortion (DCD) Param
- InterSymbol Interference (ISI) Param
- District Detterm district
- DDj Plot (by Pattern or N-bit Sequence)
- DDj Histogram
- · ISI Plot (by Pattern)

· Digital Pattern display

Reference Lane

 Compare current acquisition to Reference with a side-by-side or single (tabbed) display mode

SDAIII "LinQ" Capability

(SDAIII-LinQ, SDAIII-CrossLinQ, and SDAIII-CompleteLinQ Options)

In addition to all SDAIII capabilities, "LinQ" options includes 4 lanes of simultaneous serial data analysis plus the reference lane. If EyeDrII or VirtualProbe are purchased with SDAIII "LinQ" capability, then those capabilities are provided for all four lanes.

Lanescape Comparison Mode

When multiple lanes are enabled for display, Lanescape Comparison Modes is used. Selections for this mode are as follows:

- · Single: One lane is displayed at a time.
- · Dual: Two lanes are selected for display.
- · Mosaic: All enabled lanes are displayed

SDAIII "Crosstalk" Capability (Included in SDAIII-Crosstalk and SDAIII-CrossLinQ Options)

In addition to all SDAIII capabilities, "Crosstalk" options add the following noise and crosstalk measurements and analysis tools:

- Total, Random and Deterministic noise (Tn, Rn, Dn) measurements
- Breakdown of Dn into InterSymbol Interference noise (ISIn) and Periodic noise (Pn)
- Noise-based eye height and width: EH(BER) and EW(BER)
- Random noise (Rn) + Bounded Uncorrelated noise (BUn) Noise Histogram
- · Q-fit for Noise Histogram
- Rn+BUn Noise Spectrum and Peak threshold
- Pn Inverse FFT Plot
- Rn+BUn Noise Track
- · Crosstalk Eye Contour Plot

SDAIII-CompleteLinQ

The ultimate in serial data single or multi-lane link analysis. Provides all the capabilities mentioned above in SDAIII, "LinQ", and "Crosstalk", and also includes EyeDrII and Virtual Probe capabilities.

Eye Doctor II Advanced Signal Integrity Tools (WM8Zi-EYEDRII)

Complete set of channel emulation, de-embedding and receiver equalization simulation tools. Provides capability to emulate a serial data link, de-embed or embed a fixture, cable or serial data channel, add or remove emphasis, and perform CTLE, FFE, or DFE equalization. If purchased with SDAIII, then capabilities are accessed from within the SDAIII-CompleteLinQ user interface framework.

Virtual Probe Signal Integrity Tools (WM8Zi-VIRTUALPROBE)

Provides ability to define a complex serial data channel or topology with up to six circuit elements that may be embedded or de-embedded, allowing "probing" at a location different than the measured position. If purchased with SDAIII and EyeDrII (or with the EYEDRII-VP or CompleteLinQ options), then capabilities are accessed from within the single SDAIII-CompleteLinQ user interface framework.

Software Options (cont'd)

Clock and Clock-Data Timing Jitter Analysis Package (WM8Zi-JITKIT)

Provides convenient setup and four views of jitter (statistical, time, spectrum, and overlaid) for a variety of horizontal, amplitude, and timing parameters. Direct display of jitter measurement values. Supports multiple simultaneous views with fast selection of multiple parameter measurements for fast and easy validation.

Cable De-embedding (WM8Zi-CBL-DE-EMBED) (Standard on SDA 8 Zi-B and DDA 8 Zi-B)

Removes cable effects from your measurements. Simply enter the S-parameters or attenuation data of the cable(s) then all of the functionality of the SDA 8 Zi can be utilized with cable effects de-embedded.

8b/10b Decode (WM8Zi-8B10B D) (Standard on SDA 8 Zi-B and DDA 8 Zi-B)

Intuitive, color-coded serial decode with powerful search capability enables captured waveforms to be searched for user-defined sequences of symbols. Multi-lane analysis decodes up to four simultaneously captured lanes.

Spectrum Analyzer Mode (WM8Zi-SPECTRUM)

This package provides a new capability to navigate waveforms in the frequency domain using spectrum analyzer type controls. FFT capability added to include:

- Power averaging
- Freq domain parameters
- Power density
- FFT on up to 128 Mpts
- · Real and image components

Disk Drive Measurements Package (WM8Zi-DDM2) (Standard on DDA 8 Zi-B)

This package provides disk drive parameter measurements and related mathematical functions for performing disk drive WaveShape Analysis. Disk Drive Parameters are as follows:

- amplitude asymmetry
- local base
- local baseline separation
- local maximum
- local minimum
- local number
- local peak-peak
- local time between events
- local time between peaks
- local time between troughs
- local time at minimum
- local time at maximum
- local time peak-trough
- local time over threshold

- local time trough-peak
- local time under threshold
- narrow band phase
- narrow band power
- overwrite
- pulse width 50
- pulse width 50 -
- pulse width 50 +
- resolution
- track average amplitude
- track average amplitude -
- track average amplitude +
- auto-correlation s/n
- non-linear transition shift

ORDERING INFORMATION

Product Description	Product Code	Product Description	Product Code
WaveMaster 8 Zi-B Series Oscilloscopes		Included with Standard Configuration	
4 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 804Zi-B	÷10, 500 MHz Passive Probe (Qty. 4 on 4 – 20 GHz units, Qty. 2 on 25 – 45 GHz units))	
6 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 806Zi-B	ProLink to SMA Adapter: 4 each (for 4 – 8 GHz units) ProLink to K/2.92 mm Adapter: 4 each (for 13 – 45 GHz units)	LPA-SMA-A nits) LPA-K-A
8 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 MΩ Inputs	WaveMaster 808Zi-B	Optical 3-button Wheel Mouse, USB 2.0 Protective Front Cover	
13 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 813Zi-B	Printed Getting Started Manual	
16 GHz, 80 GS/s, 64 Mpts/Ch DSO with 15.3" WXGA Color	WaveMaster 816Zi-B	Anti-virus Software (Trial Version) Microsoft Windows 7 License	
Display. 50 Ω and 1 M Ω Inputs. Also operates in 4ch, 40 GS/s, 32 Mpts/Ch mode.		Commercial NIST Traceable Calibration with Certificate Power Cable for the Destination Country	
20 GHz, 80 GS/s, 64 Mpts/Ch DSO with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs. Also operates in 4ch, 40 GS/s, 32 Mpts/Ch mode.	WaveMaster 820Zi-B	3-year Warranty	
25 GHz, 80 GS/s, 64 Mpts/Ch Digital Bandwidth Interleaved (DBI) Oscilloscope with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs. Also operates in 20 GHz, 40 GS/s, 4ch, 32 Mpts/Ch mode.	WaveMaster 825Zi-B	Memory and Sample Rate Options 80 GS/s on 2 Ch Sampling Rate Option for WaveMaster 8 Zi-B (not available for 816Zi-B, 820Zi-B, 825Zi-B or 830Zi-B). Includes two separate external	WM8Zi-2X80GS
30 GHz, 80 GS/s, 64 Mpts/Ch Digital Bandwidth Interleaved (DBI) Oscilloscope with 15.3" WXGA Color	WaveMaster 830Zi-B	interleaving devices with storage case 32 Mpts/Ch Standard Memory for WaveMaster 8 Zi-B.	WM8Zi-STD
Display. 50 Ω and 1 M Ω Inputs. Also operates in 20 GHz, 40 GS/s, 4ch, 32 Mpts/Ch mode.		Includes 8 GB of RAM 64 Mpts/Ch Standard Memory for SDA 8 Zi-B	SDA8Zi-STD
SDA 8 Zi-B Series Serial Data Analyzers		Includes 8 GB of RAM 64 Mpts/Ch Memory Option for WaveMaster 8 Zi-B	WM8Zi-M-64
4 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs,	SDA 804Zi-B	128 Mpts/Ch Memory Option for WaveMaster 8 Zi-B	WM8Zi-L-128
6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.		128 Mpts/Ch Memory Option for SDA 8 Zi-B	SDA8Zi-L-128
6 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs,	SDA 806Zi-B	256 Mpts/Ch Memory Option for WaveMaster 8 Zi-B 256 Mpts/Ch Memory Option for SDA 8 Zi-B	WM8Zi-VL-256 SDA8Zi-VL-256
6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode. 8 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer	SDA 808Zi-B	256 Mpts/Ch Memory Option for DDA 8 Zi-B	DDA8Zi-VL-256
with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.		CPU, Computer and Other Hardware Options	
13 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer	SDA 813Zi-B	Upgrade from 160 GB Hard Drive to 500 GB Hard Drive	WM8Zi-500GB-HD
with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.		GPIB Option for Teledyne LeCroy Oscilloscope. Half-height Card	GPIB-4
16 GHz, 80 GS/s, 128 Mpts/Ch Serial Data Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.	SDA 816Zi-B	8 GB to 32 GB CPU RAM Option W	/M8Zi-8-UPG-16GBRAM /M8Zi-8-UPG-32GBRAM
Also operates in 4ch, 40 GS/s, 64 Mpts/Ch mode. 20 GHz, 80 GS/s, 128 Mpts/Ch Serial Data Analyzer with	SDA 820Zi-B	Serial Data and CrossTalk Analysis Complete Multi-Lane SDA LinQ WM87	Zi ODAIII O latatia
15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs,		Framework, including Eye, Jitter, Noise,	Zi-SDA III -CompleteLinQ SDA8Zi-CompleteLinQ
6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode. Also operates in 4ch, 40 GS/s, 64 Mpts/Ch mode.		Crosstalk Measurements, with EyeDrII	DDA8Zi-CompleteLinQ
25 GHz,80 GS/s, 128 Mpts/Ch Digital Bandwidth Interleaved (DBI) Serial Data Analyzer - 15.3" WXGA Color	SDA 825Zi-B	and VirtualProbe	
Display. 50 $\hat{\Omega}$ and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger,		Multi-Lane Serial Data Analysis LinQ WI Framework, Eye, Jitter, Noise and	M8Zi-SDAIII-CrossLinQ
and 8b/10b and 64b/66b decode. Also operates in 20 GHz, 40 GS/s, 4ch, 64 Mpts/Ch mode.		Crosstalk Measurements	SDA8Zi-CrossLinQ DDA8Zi-CrossLinQ
30 GHz,80 GS/s, 128 Mpts/Ch Digital Bandwidth	SDA 830Zi-B	Multi-Lane Serial Data Analysis LinQ	WM8Zi-SDA III -LinO
Interleaved (DBI) Serial Data Analyzer - 15.3" WXGA Color	00/1000210	Framework, Eye and Jitter	SDA8Zi-LinQ
Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, and 8b/10b and 64b/66b decode. Also operates in		Measurements	DDA8Zi-LinQ
20 GHz, 40 GS/s, 4ch, 64 Mpts/Ch mode.			/M8Zi-SDA III -Crosstalk
		Framework, Eye, Jitter, Noise and	SDA8Zi-Crosstalk DDA8Zi-Crosstalk
DDA 8 Zi-B Series Oscilloscopes		Crosstalk Measurements Single-Lane Serial Data Analysis Framework,	WM8Zi-SDA III
6 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Disk Drive Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs.		Eye and Jitter Measurements	
8 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Disk Drive Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs.	DDA 808Zi-B	PAM4 Signal Analysis	WM8Zi-PAM4
20 GHz, 80 GS/s, 128 Mpts/Ch Disk Drive Analyzer with	DDA 820Zi-B	Signal Integrity Toolkits	
15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs. Also operates in 4ch, 40 GS/s, 64 Mpts/Ch mode.		Advanced De-embedding, Emulation and Virtual Probing Toolkit	WM8Zi-VIRTUALPROBE
		Signal Integrity Toolkit - Channel & Fixture De-embedding/Emulation, Tx/Rx Equalization	WM8Zi-EYEDRII
		Bundle - EyeDrll and VirtualProbe Toolkits	WM8Zi-EYEDRII-VP
			WM8Zi-CBL-DE-EMBED
		Modulated Signal Analysis	
		VectorLinQ – Flexible vector signal analysis for electrical signals (RF and baseband I-Q)	WM8Zi-VECTORLINQ
		Optical-LinQ — Coherent optical modulation analysis	WM8Zi-OPTICAL-LINQ
		•	·

ORDERING INFORMATION

Product Description	Product Code	Product Description	Product Code
High-speed Digital Analyzer Systems		Serial Data Triggers and Decoders	
12.5 GS/s High-speed Digital Analyzer with 18ch QuickLink leadset and LBUS connection 12.5 GS/s High-speed Digital Analyzer with 9ch	HDA125-18-LBUS	80-bit NRZ, 8b/10b, and 64b/66b 6.5 Gbps Serial Trigger option. Also includes 8b/10b and 64b/66b decode. (Standard on	WM8Zi-6GBIT-80b-SYMBOL-TD
QuickLink leadset and LBUS connection			M8Zi-14GBIT-80b-SYMBOL-TD 8Zi-UPG-14GBIT-80b-SYMBOL-TD
DDR Debug Tookits DDR2 and LPDDR2 Debug Toolkit	WM8ZI-DDR2-TOOLKIT	cludes 8b/10b and 64b/66b decode.	
DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 Debug Toolkit	WM8ZI-DDR3-TOOLKIT	64b/66b Decode Annotation Option 8b/10b Decode Annotation Option ENET Decode Option	WM8Zi-64b66b D WM8Zi-8B10B D WM8Zi-ENETbus D
DDR4, DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 Debug Toolkit	WM8ZI-DDR4-TOOLKIT	Ethernet 10G Decode Option PCI Express Decode Annotation Option	WM8Zi-ENET10Gbus D
DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 Debug Toolkit Upgrade	VM8ZI-UPG-DDR3-TOOLKIT	USB 3.0 Decode Annotation Option	WM8Zi-PCIEbus D WM8Zi-USB3bus D
	VM8ZI-UPG-DDR4-TOOLKIT	USB 2.0 Decode Annotation Option USB2-HSIC Decode Option SATA Decode Annotation Option	WM8Zi-USB2bus D WM8Zi-USB2-HSICbus D WM8Zi-SATAbus D
Serial Data Compliance		SAS Decode Annotation Option	WM8Zi-SASbus D
QualiPHY Enabled 10GBase-KR Software Option	QPHY-10GBase-KR	Fibre Channel Decode Annotation Option	WM8Zi-FCbus D
QualiPHY Enabled 10GBase-T Software Option	QPHY-10GBASE-T	D-PHY Decode Option	WM8Zi-DPHYbus D
QualiPHY Enabled BroadR-Reach Software Option	QPHY-BroadR-Reach	DigRF 3G Decode Option DigRF v4 Decode Option	WM8Zi-DigRF3Gbus D WM8Zi-DIGRFv4bus D
QualiPHY Enabled DDR2 Software Option QualiPHY Enabled DDR3 Software Option	QPHY-DDR2	Audiobus Trigger and Decode Option	WM8Zi-Audiobus TD
QualiPHY Enabled DDR4 Software Option QualiPHY Enabled DDR4 Software Option	QPHY-DDR3 QPHY-DDR4	for I ² S, LJ, RJ, and TDM	
QualiPHY Enabled DisplayPort Software Option QualiPHY Enabled Embedded DisplayPort Software Option	QPHY-DisplayPort	Audiobus Trigger, Decode, and Graph Option for I ² S, LJ, RJ, and TDM	WM8Zi-Audiobus TDG
QualiPHY Enabled Ethernet 10/100/1000BT Software		Manchester Decode Option MIPI D-PHY Decode Annotation Option	WM8Zi-Manchesterbus D
QualiPHY Enabled HDMI 1.4 and HDMI 2 Software Opti		MIPI D-PHY Decode Annotation Option MIPI D-PHY Decode and Physical Layer Test Opt	WM8Zi-DPHYbus D tion WM8Zi-DPHYbus DP
QualiPHY Enabled LPDDR2 Software Option	QPHY-LPDDR2	MIPI M-PHY Decode Annotation Option	WM8Zi-MPHYbus D
QualiPHY Enabled MIPI D-PHY Software Option	QPHY-MIPI-DPHY	MIPI M-PHY Decode Annotation and	WM8Zi-MPHYbus DP
QualiPHY Enabled MIPI M-PHY Software Option QualiPHY Enabled MOST50 ePHY Software Option	QPHY-MIPI-MPHY QPHY-MOST50	Physical Layer Test Option	
QualiPHY Enabled MOST150 oPHY Software Option	QPHY-MOST150	MIPI UniPro Protocol Decode Option	WM8ZI-UNIPROBUS D WM8ZI-SPACEWIREBUS D
QualiPHY Enabled PCIe 3.0 Software Option	QPHY-PCle3	SpaceWire Decode Option 12C Bus Trigger and Decode Option	WM8Zi-I2Cbus TD
QualiPHY Enabled PCIe Gen1 Software Option	QPHY-PCle	SPI Bus Trigger and Decode Option	WM8Zi-SPIbus TD
QualiPHY Enabled SATA Software Option	QPHY-SATA-TSG-RSG	LIN Trigger and Decode Option	WM8Zi-LINbus TD
QualiPHY Enabled SAS-2 Software Option QualiPHY Enabled SAS-3 Software Option	QPHY-SAS2	UART and RS-232 Trigger	WM8Zi-UART-RS232bus TD
QualiPHY Enabled SAS-3 Software Option QualiPHY Enabled SFI Software Option	QPHY-SAS3 QPHY-SFI	and Decode Option FlexRay Trigger and Decode Option	WM8Zi-FlexRaybus TD
QualiPHY Enabled USB 2.0 Software Option	OPHY-USB [‡]	FlexRay Trigger, Decode, and	WM8Zi-FlexRaybus TDP
QualiPHY Enabled USB 3.0 Transmitter/ Receiver Com	- QPHY-USB3-Tx-Rx	Physical Layer Test Option	
pliance Software Option QualiPHY Enabled USB 3.1 Transmitter/ Receiver Com	ODLIV LICES 1 Ty Dy	SENT Decode Option CANbus TD Trigger and Decode Option	WM8Zi-SENTbus D WM8Zi-CANbus TD
pliance Software Option	· UPHY-USB3.1-1X-RX	CAN FD Trigger and Decode Option	WM8Zi-CAN FDbus TD
*TF-ENET-B required. [†] TF-HDMI-3.3V-QUADPAK require		CAN Trigger, Decode and Measure/Graph Option	WM8Zi-CANbus TDM
PCI Express, SuperSpeed USB (USB 3.0) and SATA Complet Solutions are available. Consult Factory.	e Hardware/Software Test	CAN FD Trigger, Decode and Measure/Graph Optio	
Solutions are available. Consult ractory.		MIL-STD-1553 Trigger and Decode Option	WM8Zi-1553 TD
Serial Data Test Fixtures			M8Zi-BRINC429bus DSymbolic
Test Fixture for 10GBase-T	TF-10GBASE-T	PROTObus MAG Serial Debug Toolkit Decode Annotation and Protocol Analyzer	WM8Zi-PROTObus MAG WM8Zi-ProtoSync
10/100/1000Base-T Ethernet Test Fixture Telecom Adapter Kit 100 Ω Bal., 120 Ω Bal., 75 Ω Unba	TF-ENET-B*	Synchronization Software Option	
HDMI 50Ω Pull-Up Terminator	TF-HDMI-3.3V	Decode Annotation and Protocol Analyzer + BitTracer Synchronization Software Option	WM8Zi-ProtoSync-BT
HDMI Pull-Up Terminator Quad Pack SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s Compliance Test Fixture	TF-HDMI-3.3V-QUADPAK TF-SATA-C	High-speed Digitizer Output High-speed PCIe Gen1 x4 Digitizer Output	LSIB-1
SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s	TF-SATA-C-KIT	PCI Express x1 Host Interface Board for Desktop	
Compliance Test Fixture Measure Kit USB 2.0 Compliance Test Fixture	TF-USB-B	PCI Express x1 Express Card Host Interface for Laptop Express Card Slot	LSIB-HOSTCARD
USB 3.0 and 3.1 Compliance Test Fixture 2 x BNC to SMA Adapter	TF-USB3 ENET-2ADA-BNCSMA	PCI Express x4 3-meter Cable with x4 Cable Connectors Included	LSIB-CABLE-3M
2 x 18 inch SMA to SMA Cable 2 x 36 inch SMA to SMA Cable	ENET-2CAB-SMA018 ENET-2CAB-SMA036	PCI Express x4 7-meter Cable with x4 Cable Connectors Included	LSIB-CABLE-7M
	RISE-TIME-FILTER-100PS RISE-TIME-FILTER-150PS	Mixed Signal Testing Options	
20 dB SMA Attenuators	ODB-SMA-ATTENUATOR	500 MHz, 2 GS/s, 18 Ch, 50 Mpts/Ch Mixed Signal Oscilloscope Option	MS-500
*Includes ENET-2CAB-SMA018 and ENET-2ADA-BNCSMA		250 MHz, 1 GS/s, 36 Ch, 25 Mpts/Ch (500 MHz, 18 Ch, 2 GS/s, 50 Mpts/Ch Interleave Mixed Signal Oscilloscope Option	
		250 MHz, 1 GS/s, 18 Ch, 10 Mpts/Ch Mixed Signal Oscilloscope Option	MS-250

ORDERING INFORMATION

Product Description Product Code Product Description Product Code

General Purpose and Application Specific Software Options

Spectrum Analysis Option	WM8Zi-SPECTRUM
Coherent Optical Analysis Software	WM8ZI-OPTICAL-LINQ
Digital Filter Software Package	WM8Zi-DFP2
Serial Data Mask Software Package	WM8Zi-SDM
Disk Drive Measurements Software Package	WM8Zi-DDM2
Disk Drive Analyzer Software Package	WM8Zi-DDA
Advanced Optical Recording Measurement Package	WM8Zi-BORM
Electrical Telecom Mask Test Software Package	WM8Zi-ET-PMT
EMC Pulse Parameter Software Package	WM8Zi-EMC
Power Analysis Option	WM8Zi-PWR
Clock Jitter Analysis with Four Views Software Package	wm8Zi-JITKIT

General Accessories

Keyboard, USB	KYBD-1
Probe Deskew and Calibration Test Fixture	TF-DSQ
Hard Carrying Case	WM8Zi-HARDCASE
Soft Carrying Case	WM8Zi-SOFTCASE
Rackmount Accessory for WM8Zi	WM8Zi-RACKMOUNT
ProLink to SMA Adapter	LPA-SMA-A
Kit of ProLink to SMA Adapters	LPA-SMA-KIT-A
ProLink to K/2.92 mm Adapter	LPA-K-A
Kit of ProLink to K/2.92 mm Adapters	LPA-K-KIT-A
Oscilloscope Cart with Additional Shelf and Drawer	OC1024
Oscilloscope Cart	OC1021

Probes and Probe Accessories

Flobes and Flobe Accessories	
1.0 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS1000
1.5 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS1500
2.5 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS2500
4.0 GHz, 0.6 pF, 1 MΩ High Impedance Active Probe	ZS4000
200 MHz, 3.5 pF, 1 MΩ Active Differential Probe	ZD200
25 MHz High Voltage Differential Probe	HVD3102
1kV, 25 MHz High Voltage Differential Probe without tip Accessories	HVD3102-NOACC
120 MHz High Voltage Differential Probe	HVD3106
1kV, 120 MHz High Voltage Differential Probe without tip Accessories	HVD3106-NOACC
80 MHz, High Voltage Differential Probe with 6m cable	HVD3106-6M
2kV, 120 MHz High Voltage Differential Probe	HVD3206
2kV, 80 MHz High Voltage Differential Probe with 6m cab	le HVD3206-6M
6kV, 100 MHz High Voltage Differential Probe	HVD3605
500 MHz, 1.0 pF Active Differential Probe, ±8 V	ZD500
1 GHz, 1.0 pF Active Differential Probe, ±8 V	ZD1000
1.5 GHz, 1.0 pF Active Differential Probe, ±8 V	ZD1500
WaveLink 4 GHz 2.5 Vp-p Differential Probe System	D410-PS
WaveLink 4 GHz 5 Vp-p Differential Probe System	D420-PS
WaveLink 6 GHz 2.5 Vp-p Differential Probe System	D610-PS
WaveLink 6 GHz 5 Vp-p Differential Probe System	D620-PS
WaveLink 8 GHz 3.5Vp-p Differential Probe System	D830-PS
WaveLink 10 GHz 3.5Vp-p Differential Probe System	D1030-PS
WaveLink 13 GHz 3.5Vp-p Differential Probe System	D1330-PS
WaveLink 13 GHz, 2.0 Vp-p Differential Probe System	D1305-A-PS
WaveLink 16 GHz, 2.0 Vp-p Differential Probe System	D1605-A-PS
WaveLink 20 GHz, 2.0Vp-p Differential Probe System	D2005-A-PS
WaveLink 25 GHz, 2.0 Vp-p Differential Probe System	D2505-A-PS
WaveLink 4 GHz Differential Amplifier Module with Adjustable Tip	D400A-AT†
WaveLink 6 GHz Differential Amplifier Module with Adjustable Tip	D600A-AT*
WaveLink ProLink Platform/Cable Assembly (4 – 6 GHz)	WL-PLink-CASE
WaveLink ProBus Platform/Cable Assembly (4 GHz)	WL-PBus-CASE
SMA/SMP Lead Set for Dxx30 Probes	Dxx30-SMA-SMP Leads
Optical-to-Electrical Converter, DC to 9.5 GHz, 785 to 1550 nm	OE695G
7.5 GHz Low Capacitance Passive Probe (÷10, 1 kΩ; ÷20	, 500 Ω) PP066
TekProbe to ProBus Probe Adapter	TPA10

 $[\]star$ For a complete probe, order a WL-PLink-CASE Platform/Cable Assembly with the Adjustable Tip Module.

A variety of other active voltage and current probes are also available. Consult Teledyne LeCroy for more information.

Customer Service

Teledyne LeCroy oscilloscopes and probes are designed, built, and tested to ensure high reliability. In the unlikely event you experience difficulties, our digital oscilloscopes are fully warranted for three years and our probes are warranted for one year.

This warranty includes:

- No charge for return shipping
- Long-term 7-year support
- Upgrade to latest software at no charge



1-800-5-LeCroy teledynelecroy.com

Local sales offices are located throughout the world. Visit our website to find the most convenient location.

© 2016 by Teledyne LeCroy, Inc. All rights reserved. Specifications, prices, availability, and delivery subject to change without notice. Product or brand names are trademarks or requested trademarks of their respective holders.

PCI Express® is a registered trademark and/or service mark of PCI-SIG.

[†] For a complete probe, order a WL-PBUS-CASE Platform/Cable Assembly with the Adjustable Tip Module